16-bit Proprietary Microcontroller **F²MC-16FX MB966B0 Series**

MB96F6B5R/A, MB96F6B6R

DESCRIPTION

MB966B0 series is based on FUJITSU's advanced $F^2MC-16FX$ architecture (16-bit with instruction pipeline for RISC-like performance). The CPU uses the same instruction set as the established $F^2MC-16LX$ family thus allowing for easy migration of $F^2MC-16LX$ Software to the new $F^2MC-16FX$ products. $F^2MC-16FX$ product improvements compared to the previous generation include significantly improved performance - even at the same operation frequency, reduced power consumption and faster start-up time.

For high processing speed at optimized power consumption an internal PLL can be selected to supply the CPU with up to 32MHz operation frequency from an external 4MHz to 8MHz resonator. The result is a minimum

instruction cycle time of 31.2ns going together with excellent EMI behavior. The emitted power is minimized by the on-chip voltage regulator that reduces the internal CPU voltage. A flexible clock tree allows selecting suitable operation frequencies for peripheral resources independent of the CPU speed.

Note: F²MC is the abbreviation of FUJITSU Flexible Microcontroller.

FUJITSU SEMICONDUCTOR provides information facilitating product development via the following website. The website contains information useful for customers.

http://edevice.fujitsu.com/micom/en-support/



FEATURES

- Technology
 - 0.18µm CMOS
- CPU
 - F²MC-16FX CPU
 - Optimized instruction set for controller applications
 - (bit, byte, word and long-word data types, 23 different addressing modes, barrel shift, variety of pointers) • 8-byte instruction queue
 - Signed multiply (16-bit \times 16-bit) and divide (32-bit/16-bit) instructions available

• System clock

- On-chip PLL clock multiplier ($\times 1$ to $\times 8$, $\times 1$ when PLL stop)
- 4MHz to 8MHz crystal oscillator
- (maximum frequency when using ceramic resonator depends on Q-factor)
- Up to 8MHz external clock for devices with fast clock input feature
- 32.768kHz subsystem quartz clock
- 100kHz/2MHz internal RC clock for quick and safe startup, clock stop detection function, watchdog
- Clock source selectable from mainclock oscillator, subclock oscillator and on-chip RC oscillator, independently for CPU and 2 clock domains of peripherals
- The subclock oscillator is enabled by the Boot ROM program controlled by a configuration marker after a Power or External reset
- Low Power Consumption 13 operating modes (different Run, Sleep, Timer, Stop modes)

• On-chip voltage regulator

Internal voltage regulator supports a wide MCU supply voltage range (Min=2.7V), offering low power consumption

Low voltage detection function

Reset is generated when supply voltage falls below programmable reference voltage

Code Security

Protects Flash Memory content from unintended read-out

• DMA

Automatic transfer function independent of CPU, can be assigned freely to resources

- Interrupts
 - Fast Interrupt processing
 - 8 programmable priority levels
 - Non-Maskable Interrupt (NMI)

• CAN

- Supports CAN protocol version 2.0 part A and B
- ISO16845 certified
- Bit rates up to 1Mbps
- 32 message objects
- Each message object has its own identifier mask
- Programmable FIFO mode (concatenation of message objects)
- Maskable interrupt
- Disabled Automatic Retransmission mode for Time Triggered CAN applications
- Programmable loop-back mode for self-test operation

• USART

- Full duplex USARTs (SCI/LIN)
- Wide range of baud rate settings using a dedicated reload timer
- Special synchronous options for adapting to different synchronous serial protocols
- LIN functionality working either as master or slave LIN device
- Extended support for LIN-Protocol with 16-byte FIFO for selected channels to reduce interrupt load

• I²C

- Up to 400kbps
- Master and Slave functionality, 7-bit and 10-bit addressing

• A/D converter

- SAR-type
- 8/10-bit resolution
- Signals interrupt on conversion end, single conversion mode, continuous conversion mode, stop conversion mode, activation by software, external trigger, reload timers and PPGs
- Range Comparator Function
- Scan Disable Function
- ADC Pulse Detection Function

• Source Clock Timers

Three independent clock timers (23-bit RC clock timer, 23-bit Main clock timer, 17-bit Sub clock timer)

• Hardware Watchdog Timer

- Hardware watchdog timer is active after reset
- Window function of Watchdog Timer is used to select the lower window limit of the watchdog interval
- Reload Timers
 - 16-bit wide
 - Prescaler with $1/2^1$, $1/2^2$, $1/2^3$, $1/2^4$, $1/2^5$, $1/2^6$ of peripheral clock frequency
 - Event count function

• Free-Running Timers

- Signals an interrupt on overflow, supports timer clear upon match with Output Compare 0
- Prescaler with 1, $1/2^1$, $1/2^2$, $1/2^3$, $1/2^4$, $1/2^5$, $1/2^6$, $1/2^7$, $1/2^8$ of peripheral clock frequency

• Input Capture Units

- 16-bit wide
- Signals an interrupt upon external event
- Rising edge, Falling edge or Both (rising & falling) edges sensitive

Output Compare Units

- 16-bit wide
- Signals an interrupt when a match with Free-running Timer occurs
- A pair of compare registers can be used to generate an output signal

• Programmable Pulse Generator

- 16-bit down counter, cycle and duty setting registers
- Can be used as 2×8 -bit PPG
- Interrupt at trigger, counter borrow and/or duty match
- PWM operation and one-shot operation
- Internal prescaler allows 1, 1/4, 1/16, 1/64 of peripheral clock as counter clock or of selected Reload timer underflow as clock input
- Can be triggered by software or reload timer
- Can trigger ADC conversion
- Timing point capture
- Start delay



• Quadrature Position/Revolution Counter (QPRC)

- Up/down count mode, Phase difference count mode, Count mode with direction
- 16-bit position counter
- 16-bit revolution counter
- Two 16-bit compare registers with interrupt
- Detection edge of the three external event input pins AIN, BIN and ZIN is configurable

• LCD Controller

- LCD controller with up to 4COM × 36SEG
- Internal or external voltage generation
- Duty cycle: Selectable from options: 1/2, 1/3 and 1/4
- Fixed 1/3 bias
- Programmable frame period
- Clock source selectable from four options (main clock, peripheral clock, subclock or RC oscillator clock)
- Internal divider resistors or external divider resistors
- On-chip data memory for display
- LCD display can be operated in Timer Mode
- Blank display: selectable
- All SEG, COM and V pins can be switched between general and specialized purposes

Sound Generator

- 8-bit PWM signal is mixed with tone frequency from 16-bit reload counter
- PWM clock by internal prescaler: 1, 1/2, 1/4, 1/8 of peripheral clock

• Real Time Clock

- Operational on main oscillation (4MHz), sub oscillation (32kHz) or RC oscillation (100kHz/2MHz)
- Capable to correct oscillation deviation of Sub clock or RC oscillator clock (clock calibration)
- Read/write accessible second/minute/hour registers
- Can signal interrupts every half second/second/minute/hour/day
- Internal clock divider and prescaler provide exact 1s clock

• External Interrupts

- Edge or Level sensitive
- Interrupt mask bit per channel
- Each available CAN channel RX has an external interrupt for wake-up
- Selected USART channels SIN have an external interrupt for wake-up

Non Maskable Interrupt

- Disabled after reset, can be enabled by Boot-ROM depending on ROM configuration block
- Once enabled, can not be disabled other than by reset
- High or Low level sensitive
- Pin shared with external interrupt 0

• I/O Ports

- Most of the external pins can be used as general purpose I/O
- All push-pull outputs (except when used as I²C SDA/SCL line)
- Bit-wise programmable as input/output or peripheral signal
- Bit-wise programmable input enable
- One input level per GPIO-pin (either Automotive or CMOS hysteresis)
- Bit-wise programmable pull-up resistor
- Some pins offer high current output capability for LED driving.

Built-in On Chip Debugger (OCD)

- One-wire debug tool interface
- Break function:
 - Hardware break: 6 points (shared with code event)
 - Software break: 4096 points
- Event function
 - Code event: 6 points (shared with hardware break)
 - Data event: 6 points
 - Event sequencer: 2 levels + reset
- Execution time measurement function
- Trace function: 42 branches
- Security function

• Flash Memory

I

- Dual operation flash allowing reading of one Flash bank while programming or erasing the other bank
- Command sequencer for automatic execution of programming algorithm and for supporting DMA for programming of the Flash Memory
- Supports automatic programming, Embedded Algorithm
- Write/Erase/Erase-Suspend/Resume commands
- A flag indicating completion of the automatic algorithm
- Erase can be performed on each sector individually
- Sector protection
- Flash Security feature to protect the content of the Flash
- Low voltage detection during Flash erase or write

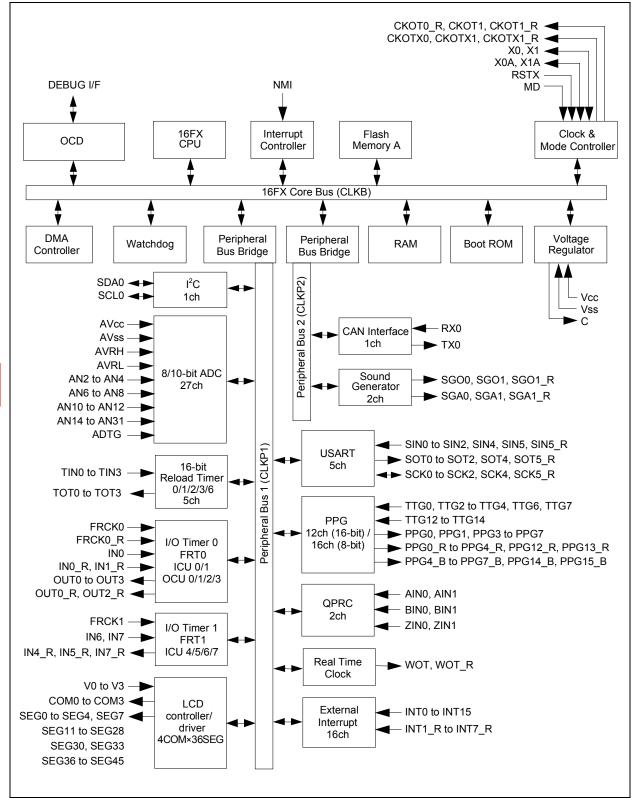
■ PRODUCT LINEUP

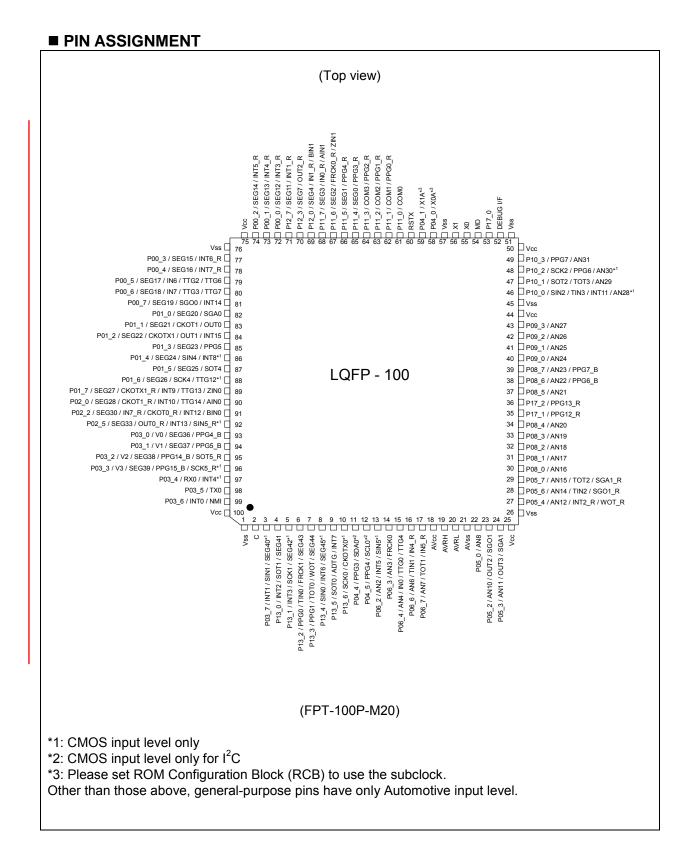
	Features		MB966B0	Remark
Product Type			Flash Memory Product	
Subclock		Subclock can be set by software		
Dual Operation Flash Memory RAM		-		
	8.5KB + 32KB	8KB	MB96F6B5R, MB96F6B5A	Product OptionsR: MCU with CAN
250	6.5KB + 32KB	16KB	MB96F6B6R	A: MCU without CAN
Package			LQFP-100 FPT-100P-M20	
DMA			4ch	
USART			5ch	LIN-USART 0 to 2/4/5
	with automatic LIN-F transmission/receptio with 16 byte RX- and TX-FIFO	n	2ch	LIN-USART 0/1
I ² C	-		1ch	$I^2C 0$
	A/D Converter		27ch	AN 2 to 4/6 to 8/10 to 12 14 to 31
	with Data Buffer		No	
	with Range Compara	tor	Yes	
	with Scan Disable		Yes	
	with ADC Pulse Dete	ction	Yes	
16-bit Re	load Timer (RLT)		5ch	RLT 0 to 3/6
	e-Running Timer (FRT	')	2ch	FRT 0/1
16-bit Inp	out Capture Unit (ICU)	,	6ch (5 channels for LIN-USART)	ICU 0/1/4 to 7 (ICU 0/1/4 to 6 for LIN-USART)
16-bit Output Compare Unit (OCU) 8/16-bit Programmable Pulse Generator (PPG)		4ch	OCU 0 to 3	
		12ch (16-bit) / 16ch (8-bit)	PPG 0 to 7/12 to 15	
	with Timing point cap	oture	Yes	
	with Start delay		Yes	
	with Ramp		No	
Quadratur (QPRC)	re Position/Revolution	Counter	2ch	QPRC 0/1
CAN Inte	erface		lch	CAN 0 32 Message Buffers
External I	Interrupts (INT)		16ch	INT 0 to 15
	kable Interrupt (NMI)		lch	
	enerator (SG)		2ch	SG 0/1
LCD Controller		4COM × 36SEG	COM 0 to 3 SEG 0 to 4/7/11 to 28/30 33/36 to 45	
Real Time	e Clock (RTC)		lch	
I/O Ports Clock Calibration Unit (CAL) Clock Output Function		77 (Dual clock mode) 79 (Single clock mode)		
		lch		
		2ch		
Low Volta	age Detection Function		Yes	Low voltage detection function can be disabled by software
	Watchdog Timer		Yes	
On-chip F	RC-oscillator		Yes	
On chin I	Debugger		Yes	



Note: All signals of the peripheral function in each product cannot be allocated by limiting the pins of package. It is necessary to use the port relocate function of the general I/O port according to your function use.

BLOCK DIAGRAM





■ PIN DESCRIPTION

PIN DESCR				
Pin name	Feature	Description		
ADTG	ADC	A/D converter trigger input pin		
AINn	QPRC	Quadrature Position/Revolution Counter Unit n input pin		
ANn	ADC	A/D converter channel n input pin		
AVcc	Supply	Analog circuits power supply pin		
AVRH	ADC	A/D converter high reference voltage input pin		
AVRL	ADC	A/D converter low reference voltage input pin		
AVss	Supply	Analog circuits power supply pin		
BINn	QPRC	Quadrature Position/Revolution Counter Unit n input pin		
С	Voltage regulator	Internally regulated power supply stabilization capacitor pin		
CKOTn	Clock Output function	Clock Output function n output pin		
CKOTn_R	Clock Output function	Relocated Clock Output function n output pin		
CKOTXn	Clock Output function	Clock Output function n inverted output pin		
CKOTXn_R	Clock Output function	Relocated Clock Output function n inverted output pin		
COMn	LCD	LCD Common driver pin		
DEBUG I/F	OCD	On Chip Debugger input/output pin		
FRCKn	Free-Running Timer	Free-Running Timer n input pin		
FRCKn_R	Free-Running Timer	Relocated Free-Running Timer n input pin		
INn	ICU	Input Capture Unit n input pin		
INn_R	ICU	Relocated Input Capture Unit n input pin		
INTn	External Interrupt	External Interrupt n input pin		
INTn R	External Interrupt	Relocated External Interrupt n input pin		
MD	Core	Input pin for specifying the operating mode		
NMI	External Interrupt	Non-Maskable Interrupt input pin		
OUTn	OCU	Output Compare Unit n waveform output pin		
OUTn_R	OCU	Relocated Output Compare Unit n waveform output pin		
Pnn_m	GPIO	General purpose I/O pin		
PPGn	PPG	Programmable Pulse Generator n output pin (16bit/8bit)		
PPGn_R	PPG	Relocated Programmable Pulse Generator n output pin (16bit/8bit)		
PPGn_B	PPG	Programmable Pulse Generator n output pin (16bit/8bit)		
RSTX	Core	Reset input pin		
RXn	CAN	CAN interface n RX input pin		
SCKn	USART	USART n serial clock input/output pin		
SCKn_R	USART	Relocated USART n serial clock input/output pin		
SCLn	I ² C	I ² C interface n clock I/O input/output pin		
SDAn	I ² C	I ² C interface n serial data I/O input/output pin		
SEGn	LCD	LCD Segment driver pin		
SGAn	Sound Generator	Sound Generator amplitude output pin		
SGAn_R	Sound Generator	Relocated Sound Generator amplitude output pin		
SGOn	Sound Generator	Sound Generator sound/tone output pin		
SGOn_R	Sound Generator	Relocated Sound Generator sound/tone output pin		
SINn	USART	USART n serial data input pin		
SINn_R	USART	Relocated USART n serial data input pin		
SOTn	USART	USART n serial data output pin		
SOTn R	USART	Relocated USART n serial data output pin		



Pin name	Feature	Description	
TINn	Reload Timer	Reload Timer n event input pin	
TOTn	Reload Timer	Reload Timer n output pin	
TTGn	PPG	Programmable Pulse Generator n trigger input pin	
TXn	CAN	CAN interface n TX output pin	
Vn	LCD	LCD voltage reference pin	
Vcc	Supply	Power supply pin	
Vss	Supply	Power supply pin	
WOT	RTC	Real Time clock output pin	
WOT_R	RTC	Relocated Real Time clock output pin	
X0	Clock	Oscillator input pin	
X0A	Clock	Subclock Oscillator input pin	
X1	Clock	Oscillator output pin	
X1A	Clock	Subclock Oscillator output pin	
ZINn	QPRC	Quadrature Position/Revolution Counter Unit n input pin	

■ PIN CIRCUIT TYPE

Pin no.	I/O circuit type*	Pin name
1	Supply	Vss
2	F	С
3	Р	P03_7 / INT1 / SIN1 / SEG40
4	J	P13_0 / INT2 / SOT1 / SEG41
5	Р	P13_1 / INT3 / SCK1 / SEG42
6	J	P13_2 / PPG0 / TIN0 / FRCK1 / SEG43
7	J	P13_3 / PPG1 / TOT0 / WOT / SEG44
8	Р	P13_4 / SIN0 / INT6 / SEG45
9	Н	P13_5 / SOT0 / ADTG / INT7
10	М	P13_6 / SCK0 / CKOTX0
11	N	P04_4 / PPG3 / SDA0
12	N	P04_5 / PPG4 / SCL0
13	Ι	P06_2 / AN2 / INT5 / SIN5
14	K	P06_3 / AN3 / FRCK0
15	K	P06_4 / AN4 / IN0 / TTG0 / TTG4
16	K	P06_6 / AN6 / TIN1 / IN4_R
17	K	P06_7 / AN7 / TOT1 / IN5_R
18	Supply	AVcc
19	G	AVRH
20	G	AVRL
21	Supply	AVss
22	K	P05_0 / AN8
23	K	P05_2 / AN10 / OUT2 / SGO1
24	K	P05_3 / AN11 / OUT3 / SGA1
25	Supply	Vcc
26	Supply	Vss
27	K	P05_4 / AN12 / INT2_R / WOT_R
28	K	P05_6 / AN14 / TIN2 / SGO1_R
29	K	P05_7 / AN15 / TOT2 / SGA1_R
30	V	P08_0 / AN16
31	V	P08_1 / AN17
32	V	P08_2 / AN18
33	V	P08_3 / AN19
34	V	P08_4 / AN20
35	Н	P17_1 / PPG12_R
36	Н	P17_2 / PPG13_R
37	V	P08_5 / AN21
38	V	P08_6 / AN22 / PPG6_B
39	V	P08_7 / AN23 / PPG7_B
40	V	P09_0 / AN24



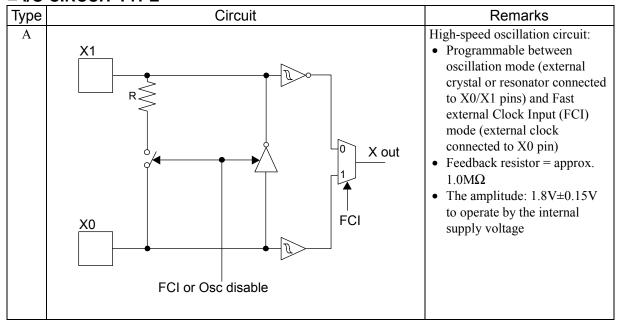
Pin no.	I/O circuit type*	Pin name	
41	V	P09_1 / AN25	
42	V	P09_2 / AN26	
43	V	P09_3 / AN27	
44	Supply	Vcc	
45	Supply	Vss	
46	W	P10_0 / SIN2 / TIN3 / INT11 / AN28	
47	V	P10_1 / SOT2 / TOT3 / AN29	
48	W	P10_2 / SCK2 / PPG6 / AN30	
49	V	P10_3 / PPG7 / AN31	
50	Supply	Vcc	
51	Supply	Vss	
52	0	DEBUG I/F	
53	Н	P17_0	
54	C	MD	
55	А	X0	
56	А	X1	
57	Supply	Vss	
58	В	P04_0 / X0A	
59	В	P04_1 / X1A	
60	С	RSTX	
61	J	P11_0 / COM0	
62	J	P11_1 / COM1 / PPG0_R	
63	J	P11_2 / COM2 / PPG1_R	
64	J	P11_3 / COM3 / PPG2_R	
65	J	P11_4 / SEG0 / PPG3_R	
66	J	P11_5 / SEG1 / PPG4_R	
67	J	P11_6 / SEG2 / FRCK0_R / ZIN1	
68	J	P11_7 / SEG3 / IN0_R / AIN1	
69	J	P12_0 / SEG4 / IN1_R / BIN1	
70	J	P12_3 / SEG7 / OUT2_R	
71	J	P12_7 / SEG11 / INT1_R	
72	J	P00_0 / SEG12 / INT3_R	
73	J	P00_1 / SEG13 / INT4_R	
74	J	P00_2 / SEG14 / INT5_R	
75	Supply	Vcc	
76	Supply	Vss	
77	J	P00_3 / SEG15 / INT6_R	
78	J	P00_4 / SEG16 / INT7_R	
79	J	P00_5 / SEG17 / IN6 / TTG2 / TTG6	
80	J	P00_6 / SEG18 / IN7 / TTG3 / TTG7	

Pin no.	I/O circuit type*	Pin name
81	J	P00_7 / SEG19 / SGO0 / INT14
82	J	P01_0 / SEG20 / SGA0
83	J	P01_1 / SEG21 / CKOT1 / OUT0
84	J	P01_2 / SEG22 / CKOTX1 / OUT1 / INT15
85	J	P01_3 / SEG23 / PPG5
86	Р	P01_4 / SEG24 / SIN4 / INT8
87	J	P01_5 / SEG25 / SOT4
88	Р	P01_6 / SEG26 / SCK4 / TTG12
89	J	P01_7 / SEG27 / CKOTX1_R / INT9 / TTG13 / ZIN0
90	J	P02_0 / SEG28 / CKOT1_R / INT10 / TTG14 / AIN0
91	J	P02_2 / SEG30 / IN7_R / CKOT0_R / INT12 / BIN0
92	Р	P02_5 / SEG33 / OUT0_R / INT13 / SIN5_R
93	L	P03_0 / V0 / SEG36 / PPG4_B
94	L	P03_1 / V1 / SEG37 / PPG5_B
95	L	P03_2 / V2 / SEG38 / PPG14_B / SOT5_R
96	Q	P03_3 / V3 / SEG39 / PPG15_B / SCK5_R
97	М	P03_4 / RX0 / INT4
98	Н	P03_5 / TX0
99	Н	P03_6 / INT0 / NMI
100	Supply	Vcc

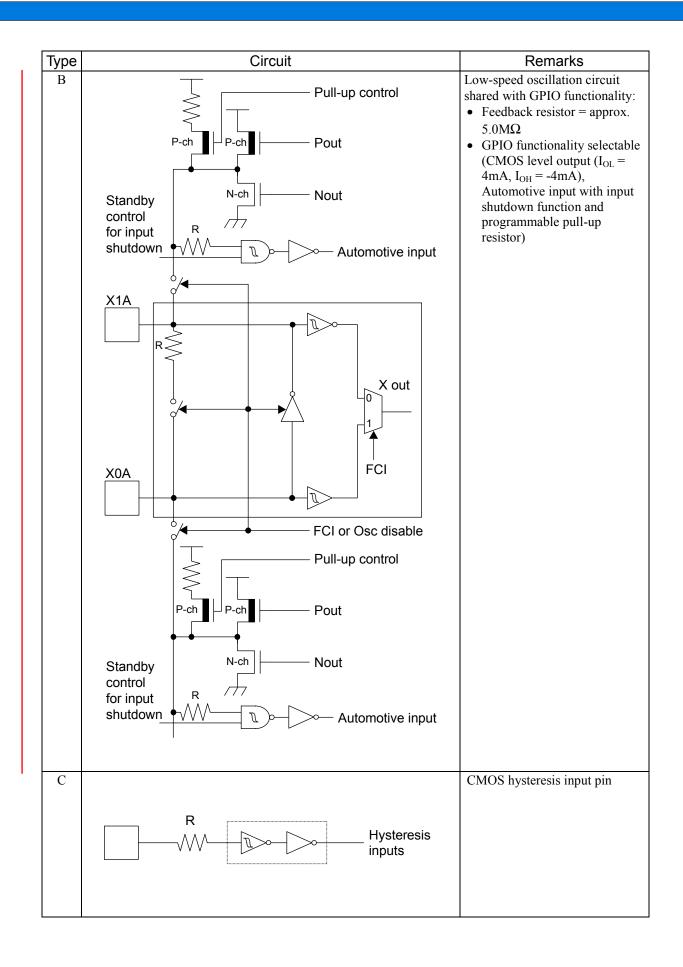
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*: See "■ I/O CIRCUIT TYPE" for details on the I/O circuit types.

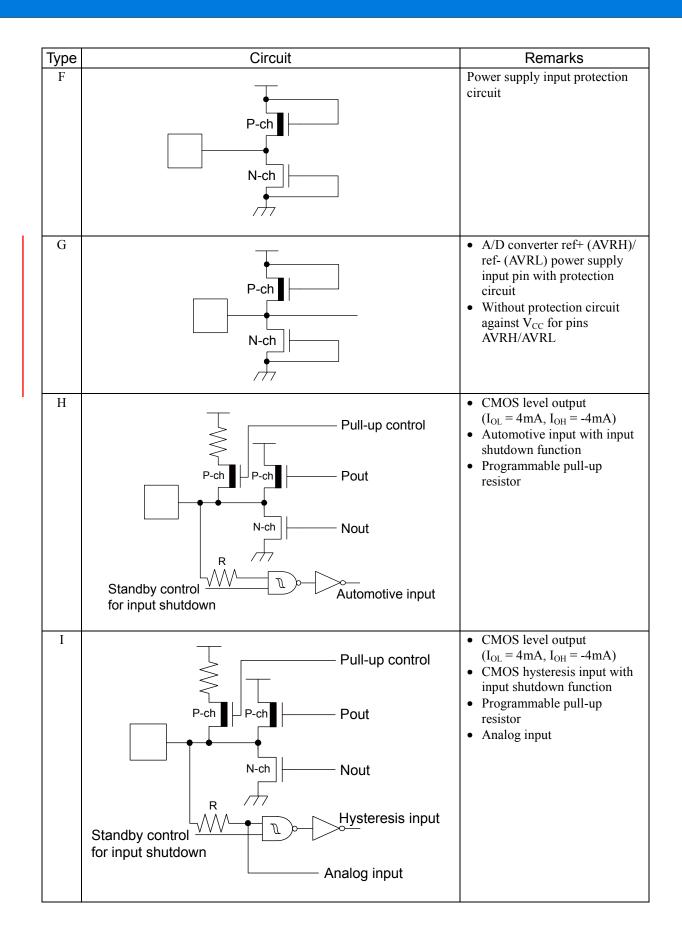
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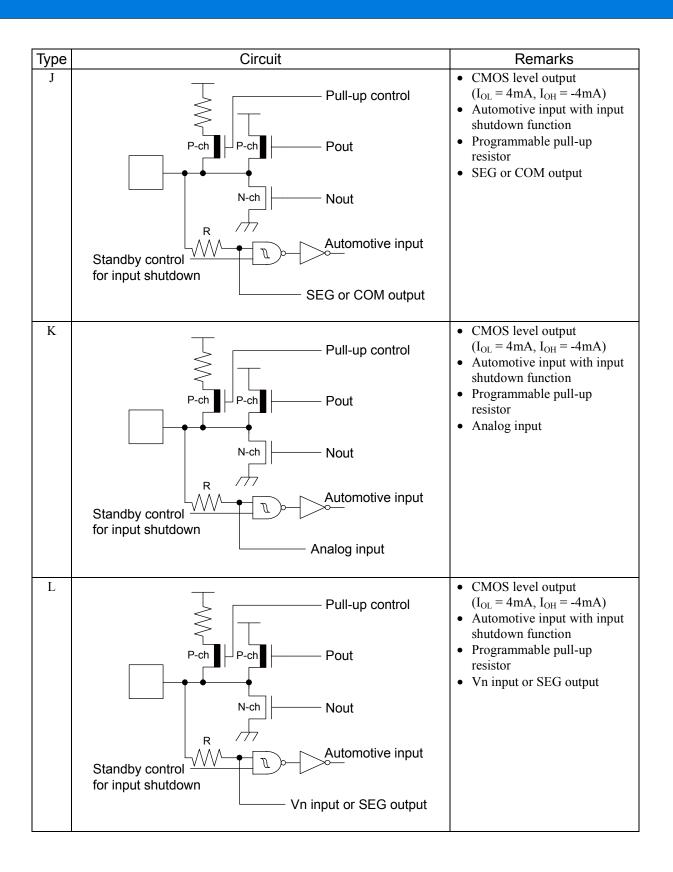


■ I/O CIRCUIT TYPE

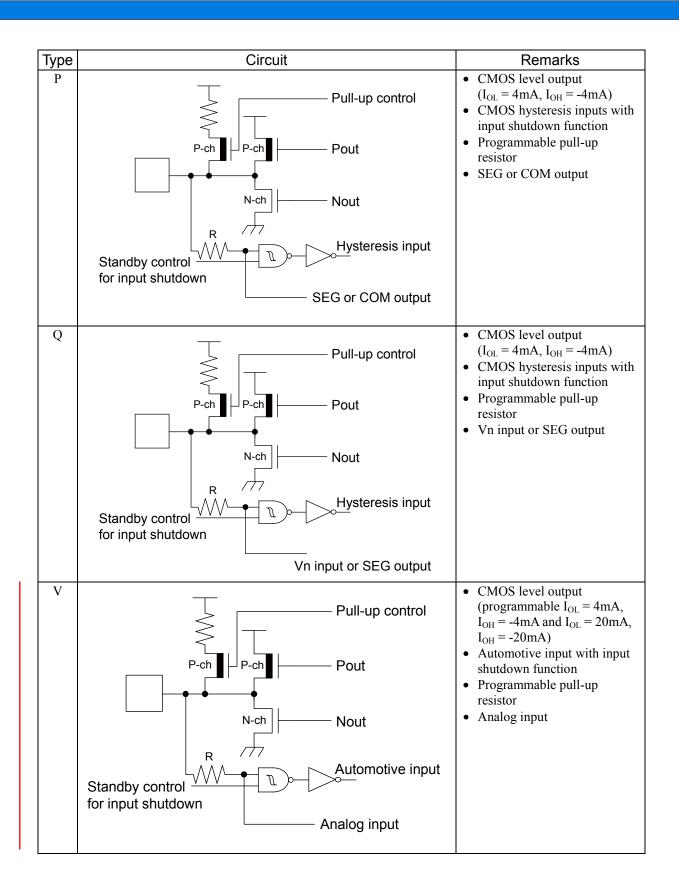


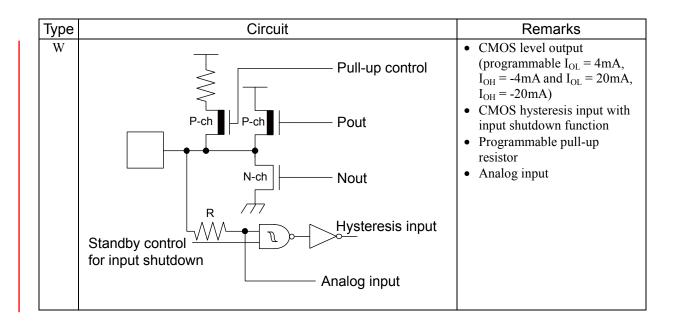
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Туре	Circuit	Remarks
M	P-ch P-ch Pout P-ch P-ch Pout P-ch Nout K K K K K K K K K K K K K K K K K K K	 CMOS level output (I_{OL} = 4mA, I_{OH} = -4mA) CMOS hysteresis input with input shutdown function Programmable pull-up resistor
N	Pull-up control P-ch P-ch Pout P-ch Nout* K Standby control for input shutdown	 CMOS level output (I_{OL} = 3mA, I_{OH} = -3mA) CMOS hysteresis input with input shutdown function Programmable pull-up resistor *: N-channel transistor has slew rate control according to I²C spec, irrespective of usage.
0	Standby control for input shutdown	 Open-drain I/O Output 25mA, Vcc = 2.7V TTL input





MEMORY MAP

FF:FFFF _H USER ROM* ¹	
DE:0000H	_
DD:FFFF _H Reserved	
0F:C000 _H Boot-ROM	
0E:9000 _H	
01:0000 _H	
00:8000 _H MIRROR	
Internal RAM	
RAMSTART0*2 bank0	_
00:0C00 _H	
00:0380 _H Peripheral	
00:0180 _H GPR*3	
00:0100 _H DMA	
<u>00:00F0_H</u> Reserved 00:0000 _H Peripheral	

*1: For details about USER ROM area, see "■USER ROM MEMORY MAP FOR FLASH DEVICES" on the following pages.

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*2: For RAMSTART addresses, see the table on the next page.

*3: Unused GPR banks can be used as RAM area.

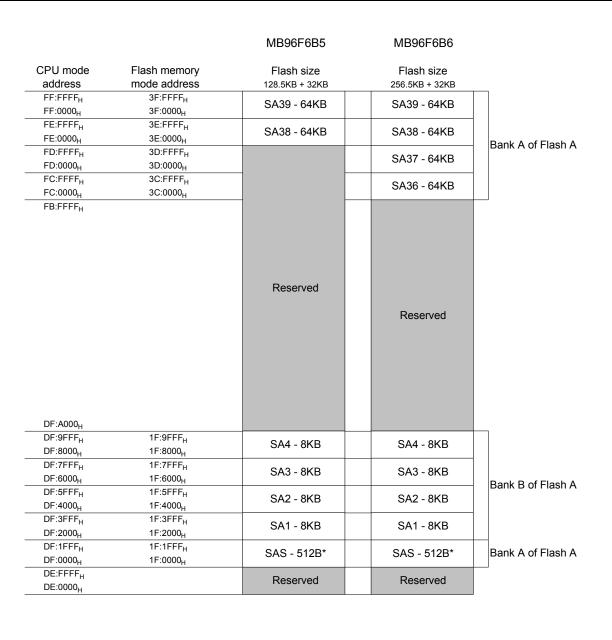
GPR: General-Purpose Register

The DMA area is only available if the device contains the corresponding resource. The available RAM and ROM area depends on the device.

■ RAMSTART ADDRESSES

Devices	Bank 0 RAM size	RAMSTART0	
MB96F6B5	8KB	$00:6200_{\rm H}$	
MB96F6B6	16KB	$00:4200_{\rm H}$	

■ USER ROM MEMORY MAP FOR FLASH DEVICES



*: Physical address area of SAS-512B is from DF:0000_H to DF:01FF_H.

Others (from DF:0200_H to DF:1FFF_H) is mirror area of SAS-512B.

Sector SAS contains the ROM configuration block RCBA at CPU address DF:0000_H -DF:01FF_H. SAS can not be used for E^2 PROM emulation.

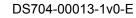
■ SERIAL PROGRAMMING COMMUNICATION INTERFACE

	MB966B0						
Pin Number	Pin Number USART Number						
8		SIN0					
9	USART0	SOT0					
10		SCK0					
3		SIN1					
4	USART1	SOT1					
5		SCK1					
46		SIN2					
47	USART2	SOT2					
48		SCK2					
86		SIN4					
87	USART4	SOT4					
88		SCK4					

USART pins for Flash serial programming (MD = 0, DEBUG I/F = 0, Serial Communication mode)

■ INTERRUPT VECTOR TABLE

		IOR TABLE			1
Vector number	Offset in vector table	Vector name	Cleared by DMA	Index in ICR to program	Description
0	3FC _H	CALLV0	No	-	CALLV instruction
1	3F8 _H	CALLV1	No	-	CALLV instruction
2	3F4 _H	CALLV2	No	-	CALLV instruction
3	3F0 _H	CALLV3	No	_	CALLV instruction
4	3EC _H	CALLV4	No	_	CALLV instruction
5	3E8 _H	CALLV5	No	_	CALLV instruction
6	3E4 _H	CALLV6	No	_	CALLV instruction
7	3E0 _H	CALLV7	No	-	CALLV instruction
8	3DC _H	RESET	No	_	Reset vector
9	3D8 _H	INT9	No	_	INT9 instruction
10	3D4 _H	EXCEPTION	No	_	Undefined instruction execution
11	3D0 _H	NMI	No	-	Non-Maskable Interrupt
12	3CC _H	DLY	No	12	Delayed Interrupt
13	3C8 _H	RC TIMER	No	13	RC Clock Timer
14	3C4 _H	MC TIMER	No	14	Main Clock Timer
15	3C0 _H	SC TIMER	No	15	Sub Clock Timer
16	3BC _H	 LVDI	No	16	Low Voltage Detector
17	3B8 _H	EXTINT0	Yes	17	External Interrupt 0
18	3B4 _H	EXTINT1	Yes	18	External Interrupt 1
19	3B0 _H	EXTINT2	Yes	19	External Interrupt 2
20	3AC _H	EXTINT3	Yes	20	External Interrupt 3
21	3A8 _H	EXTINT4	Yes	21	External Interrupt 4
22	3A4 _H	EXTINT5	Yes	22	External Interrupt 5
23	3A0 _H	EXTINT6	Yes	23	External Interrupt 6
24	39C _H	EXTINT7	Yes	24	External Interrupt 7
25	398 _H	EXTINT8	Yes	25	External Interrupt 8
26	394 _H	EXTINT9	Yes	26	External Interrupt 9
27	390 _H	EXTINT10	Yes	27	External Interrupt 10
28	38C _H	EXTINT11	Yes	28	External Interrupt 11
29	388 _H	EXTINT12	Yes	29	External Interrupt 12
30	384_{H}	EXTINT13	Yes	30	External Interrupt 13
31	380 _H	EXTINT14	Yes	31	External Interrupt 14
32	37C _H	EXTINT15	Yes	32	External Interrupt 15
33	378 _H	CAN0	No	33	CAN Controller 0
34	374 _H	-	-	34	Reserved
35	370 _H		-	35	Reserved
36	36C _H	-	-	36	Reserved
37	368 _H		-	37	Reserved
38	364 _H	PPG0	Yes	38	Programmable Pulse Generator 0
39	360 _H	PPG1	Yes	39	Programmable Pulse Generator 1
40	35C _H	PPG2	Yes	40	Programmable Pulse Generator 2



Vector number	Offset in vector table	Vector name	Cleared by DMA	Index in ICR to program	Description
41	358 _H	PPG3	Yes	41	Programmable Pulse Generator 3
42	354 _H	PPG4	Yes	42	Programmable Pulse Generator 4
43	350 _H	PPG5	Yes	43	Programmable Pulse Generator 5
44	34C _H	PPG6	Yes	44	Programmable Pulse Generator 6
45	348 _H	PPG7	Yes	45	Programmable Pulse Generator 7
46	344 _H	-	-	46	Reserved
47	340 _H	-	-	47	Reserved
48	33C _H	-	-	48	Reserved
49	338 _H	-	-	49	Reserved
50	334 _H	PPG12	Yes	50	Programmable Pulse Generator 12
51	330 _H	PPG13	Yes	51	Programmable Pulse Generator 13
52	32C _H	PPG14	Yes	52	Programmable Pulse Generator 14
53	328 _H	PPG15	Yes	53	Programmable Pulse Generator 15
54	324 _H	-	-	54	Reserved
55	320 _H	-	-	55	Reserved
56	31C _H	-	-	56	Reserved
57	318 _H	-	-	57	Reserved
58	314 _H	RLT0	Yes	58	Reload Timer 0
59	310 _H	RLT1	Yes	59	Reload Timer 1
60	30C _H	RLT2	Yes	60	Reload Timer 2
61	308 _H	RLT3	Yes	61	Reload Timer 3
62	304 _H	-	-	62	Reserved
63	300 _H	-	-	63	Reserved
64	2FC _H	RLT6	Yes	64	Reload Timer 6
65	2F8 _H	ICU0	Yes	65	Input Capture Unit 0
66	$2F4_{H}$	ICU1	Yes	66	Input Capture Unit 1
67	$2F0_{H}$	-	-	67	Reserved
68	$2EC_{H}$	-	-	68	Reserved
69	$2E8_{H}$	ICU4	Yes	69	Input Capture Unit 4
70	$2E4_{H}$	ICU5	Yes	70	Input Capture Unit 5
71	$2E0_{H}$	ICU6	Yes	71	Input Capture Unit 6
72	$2DC_{H}$	ICU7	Yes	72	Input Capture Unit 7
73	2D8 _H	-	-	73	Reserved
74	$2D4_{H}$	-	-	74	Reserved
75	$2D0_{H}$	-	-	75	Reserved
76	$2CC_{H}$	-	-	76	Reserved
77	2C8 _H	OCU0	Yes	77	Output Compare Unit 0
78	2C4 _H	OCU1	Yes	78	Output Compare Unit 1
79	2C0 _H	OCU2	Yes	79	Output Compare Unit 2
80	$2BC_{H}$	OCU3	Yes	80	Output Compare Unit 3

Vector number	Offset in vector table	Vector name	Cleared by DMA	Index in ICR to program	Description
81	2B8 _H	-	-	81	Reserved
82	2B4 _H	-	-	82	Reserved
83	$2B0_{H}$	-	-	83	Reserved
84	2AC _H	-	-	84	Reserved
85	2A8 _H	-	-	85	Reserved
86	2A4 _H	-	-	86	Reserved
87	2A0 _H	-	-	87	Reserved
88	29C _H	-	-	88	Reserved
89	298 _H	FRT0	Yes	89	Free-Running Timer 0
90	294 _H	FRT1	Yes	90	Free-Running Timer 1
91	290 _H	-	-	91	Reserved
92	28C _H	-	-	92	Reserved
93	288 _H	RTC0	No	93	Real Time Clock
94	284 _H	CAL0	No	94	Clock Calibration Unit
95	$280_{ m H}$	SG0	No	95	Sound Generator 0
96	27C _H	IIC0	Yes	96	I ² C interface 0
97	278 _H	-	-	97	Reserved
98	$274_{ m H}$	ADC0	Yes	98	A/D Converter 0
99	270 _H	-	-	99	Reserved
100	26C _H	-	-	100	Reserved
101	268_{H}	LINR0	Yes	101	LIN USART 0 RX
102	264 _H	LINT0	Yes	102	LIN USART 0 TX
103	260 _H	LINR1	Yes	103	LIN USART 1 RX
104	25C _H	LINT1	Yes	104	LIN USART 1 TX
105	258 _H	LINR2	Yes	105	LIN USART 2 RX
106	254 _H	LINT2	Yes	106	LIN USART 2 TX
107	250 _H	-	-	107	Reserved
108	24C _H	-	-	108	Reserved
109	248 _H	LINR4	Yes	109	LIN USART 4 RX
110	244 _H	LINT4	Yes	110	LIN USART 4 TX
111	240 _H	LINR5	Yes	111	LIN USART 5 RX
112	23C _H	LINT5	Yes	112	LIN USART 5 TX
113	238 _H	-	-	113	Reserved
114	234 _H	-	-	114	Reserved
115	230 _H	-	-	115	Reserved
116	22C _H	-	-	116	Reserved
117	228 _H	-	-	117	Reserved
118	224 _H	-	-	118	Reserved
119	220 _H	-	-	119	Reserved
120	21C _H	-	-	120	Reserved

	Vector number	Offset in vector table	Vector name	Cleared by DMA	Index in ICR to program	Description
	121	218 _H	SG1	No	121	Sound Generator 1
	122	214 _H	-	-	122	Reserved
ſ	123	210 _H	-	-	123	Reserved
Ī	124	20C _H	-	-	124	Reserved
Ī	125	208 _H	-	-	125	Reserved
Ī	126	204 _H	-	-	126	Reserved
ſ	127	200 _H	-	-	127	Reserved
ſ	128	1FC _H	-	-	128	Reserved
	129	$1F8_{H}$	-	-	129	Reserved
ſ	130	$1F4_{H}$	-	-	130	Reserved
ſ	131	$1 FO_{H}$	-	-	131	Reserved
	132	$1EC_{H}$	-	-	132	Reserved
	133	$1E8_{H}$	FLASHA	Yes	133	Flash memory A interrupt
	134	$1E4_{H}$	-	-	134	Reserved
	135	$1 \mathrm{E0}_\mathrm{H}$	-	-	135	Reserved
	136	1DC _H	-	-	136	Reserved
	137	$1D8_{H}$	QPRC0	Yes	137	Quadrature Position/Revolution counter 0
	138	$1D4_{H}$	QPRC1	Yes	138	Quadrature Position/Revolution counter 1
Ī	139	1D0 _H	ADCRC0	No	139	A/D Converter 0 - Range Comparator
Ī	140	1CC _H	ADCPD0	No	140	A/D Converter 0 - Pulse detection
ľ	141	1C8 _H	-	-	141	Reserved
ľ	142	1C4 _H	-	-	142	Reserved
ľ	143	1C0 _H	-	-	143	Reserved

HANDLING PRECAUTIONS

Any semiconductor devices have inherently a certain rate of failure. The possibility of failure is greatly affected by the conditions in which they are used (circuit conditions, environmental conditions, etc.). This page describes precautions that must be observed to minimize the chance of failure and to obtain higher reliability from your FUJITSU SEMICONDUCTOR semiconductor devices.

1. Precautions for Product Design

This section describes precautions when designing electronic equipment using semiconductor devices.

Absolute Maximum Ratings

Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of certain established limits, called absolute maximum ratings. Do not exceed these ratings.

Recommended Operating Conditions

Recommended operating conditions are normal operating ranges for the semiconductor device. All the device's electrical characteristics are warranted when operated within these ranges.

Always use semiconductor devices within the recommended operating conditions. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their sales representative beforehand.

Processing and Protection of Pins

These precautions must be followed when handling the pins which connect semiconductor devices to power supply and input/output functions.

(1) Preventing Over-Voltage and Over-Current Conditions

Exposure to voltage or current levels in excess of maximum ratings at any pin is likely to cause deterioration within the device, and in extreme cases leads to permanent damage of the device. Try to prevent such overvoltage or over-current conditions at the design stage.

(2) Protection of Output Pins

Shorting of output pins to supply pins or other output pins, or connection to large capacitance can cause large current flows. Such conditions if present for extended periods of time can damage the device.

Therefore, avoid this type of connection.

(3) Handling of Unused Input Pins

Unconnected input pins with very high impedance levels can adversely affect stability of operation. Such pins should be connected through an appropriate resistance to a power supply pin or ground pin.

· Latch-up

Semiconductor devices are constructed by the formation of P-type and N-type areas on a substrate. When subjected to abnormally high voltages, internal parasitic PNPN junctions (called thyristor structures) may be formed, causing large current levels in excess of several hundred mA to flow continuously at the power supply pin. This condition is called latch-up.

CAUTION: The occurrence of latch-up not only causes loss of reliability in the semiconductor device, but can cause injury or damage from high heat, smoke or flame. To prevent this from happening, do the following:

- (1) Be sure that voltages applied to pins do not exceed the absolute maximum ratings. This should include attention to abnormal noise, surge levels, etc.
- (2) Be sure that abnormal current flows do not occur during the power-on sequence.

Code: DS00-00004-1Ea



· Observance of Safety Regulations and Standards

Most countries in the world have established standards and regulations regarding safety, protection from electromagnetic interference, etc. Customers are requested to observe applicable regulations and standards in the design of products.

Fail-Safe Design

Any semiconductor devices have inherently a certain rate of failure. You must protect against injury, damage or loss from such failures by incorporating safety design measures into your facility and equipment such as redundancy, fire protection, and prevention of over-current levels and other abnormal operating conditions.

· Precautions Related to Usage of Devices

FUJITSU SEMICONDUCTOR semiconductor devices are intended for use in standard applications (computers, office automation and other office equipment, industrial, communications, and measurement equipment, personal or household devices, etc.).

CAUTION: Customers considering the use of our products in special applications where failure or abnormal operation may directly affect human lives or cause physical injury or property damage, or where extremely high levels of reliability are demanded (such as aerospace systems, atomic energy controls, sea floor repeaters, vehicle operating controls, medical devices for life support, etc.) are requested to consult with sales representatives before such use. The company will not be responsible for damages arising from such use without prior approval.

2. Precautions for Package Mounting

Package mounting may be either lead insertion type or surface mount type. In either case, for heat resistance during soldering, you should only mount under FUJITSU SEMICONDUCTOR's recommended conditions. For detailed information about mount conditions, contact your sales representative.

Lead Insertion Type

Mounting of lead insertion type packages onto printed circuit boards may be done by two methods: direct soldering on the board, or mounting by using a socket.

Direct mounting onto boards normally involves processes for inserting leads into through-holes on the board and using the flow soldering (wave soldering) method of applying liquid solder. In this case, the soldering process usually causes leads to be subjected to thermal stress in excess of the absolute ratings for storage temperature. Mounting processes should conform to FUJITSU SEMICONDUCTOR recommended mounting conditions.

If socket mounting is used, differences in surface treatment of the socket contacts and IC lead surfaces can lead to contact deterioration after long periods. For this reason it is recommended that the surface treatment of socket contacts and IC leads be verified before mounting.

Surface Mount Type

Surface mount packaging has longer and thinner leads than lead-insertion packaging, and therefore leads are more easily deformed or bent. The use of packages with higher pin counts and narrower pin pitch results in increased susceptibility to open connections caused by deformed pins, or shorting due to solder bridges.

You must use appropriate mounting techniques. FUJITSU SEMICONDUCTOR recommends the solder reflow method, and has established a ranking of mounting conditions for each product. Users are advised to mount packages in accordance with FUJITSU SEMICONDUCTOR ranking of recommended conditions.

Lead-Free Packaging

CAUTION: When ball grid array (BGA) packages with Sn-Ag-Cu balls are mounted using Sn-Pb eutectic soldering, junction strength may be reduced under some conditions of use.

Storage of Semiconductor Devices

Because plastic chip packages are formed from plastic resins, exposure to natural environmental conditions will cause absorption of moisture. During mounting, the application of heat to a package that has absorbed moisture can cause surfaces to peel, reducing moisture resistance and causing packages to crack. To prevent, do the following:

- (1) Avoid exposure to rapid temperature changes, which cause moisture to condense inside the product. Store products in locations where temperature changes are slight.
- (2) Use dry boxes for product storage. Products should be stored below 70% relative humidity, and at temperatures between 5°C and 30°C. When you open Dry Package that recommends humidity 40% to 70% relative humidity.
- (3) When necessary, FUJITSU SEMICONDUCTOR packages semiconductor devices in highly moisture-resistant aluminum laminate bags, with a silica gel desiccant. Devices should be sealed in their aluminum laminate bags for storage.
- (4) Avoid storing packages where they are exposed to corrosive gases or high levels of dust.

• Baking

Packages that have absorbed moisture may be de-moisturized by baking (heat drying). Follow the FUJITSU SEMICONDUCTOR recommended conditions for baking.

Condition: 125°C/24 h

Static Electricity

Because semiconductor devices are particularly susceptible to damage by static electricity, you must take the following precautions:

- (1) Maintain relative humidity in the working environment between 40% and 70%. Use of an apparatus for ion generation may be needed to remove electricity.
- (2) Electrically ground all conveyors, solder vessels, soldering irons and peripheral equipment.
- (3) Eliminate static body electricity by the use of rings or bracelets connected to ground through high resistance (on the level of 1 MΩ). Wearing of conductive clothing and shoes, use of conductive floor mats and other measures to minimize shock loads is recommended.
- (4) Ground all fixtures and instruments, or protect with anti-static measures.
- (5) Avoid the use of styrofoam or other highly static-prone materials for storage of completed board assemblies.

3. Precautions for Use Environment

Reliability of semiconductor devices depends on ambient temperature and other conditions as described above.

For reliable performance, do the following:

(1) Humidity

Prolonged use in high humidity can lead to leakage in devices as well as printed circuit boards. If high humidity levels are anticipated, consider anti-humidity processing.

- (2) Discharge of Static Electricity When high-voltage charges exist close to semiconductor devices, discharges can cause abnormal operation. In such cases, use anti-static measures or processing to prevent discharges.
- (3) Corrosive Gases, Dust, or Oil

Exposure to corrosive gases or contact with dust or oil may lead to chemical reactions that will adversely affect the device. If you use devices in such conditions, consider ways to prevent such exposure or to protect the devices.

(4) Radiation, Including Cosmic Radiation

Most devices are not designed for environments involving exposure to radiation or cosmic radiation. Users should provide shielding as appropriate.

(5) Smoke, Flame

CAUTION: Plastic molded devices are flammable, and therefore should not be used near combustible substances. If devices begin to smoke or burn, there is danger of the release of toxic gases. Customers considering the use of FUJITSU SEMICONDUCTOR products in other special environmental conditions should consult with sales representatives.

Please check the latest handling precautions at the following URL. http://edevice.fujitsu.com/fj/handling-e.pdf

HANDLING DEVICES

Special care is required for the following when handling the device:

- Latch-up prevention
- Unused pins handling
- External clock usage
- Notes on PLL clock mode operation
- Power supply pins (Vcc/Vss)
- Crystal oscillator and ceramic resonator circuit
- Turn on sequence of power supply to A/D converter and analog inputs
- Pin handling when not using the A/D converter
- Notes on Power-on
- Stabilization of power supply voltage
- Serial communication
- Mode Pin (MD)

1. Latch-up prevention

CMOS IC chips may suffer latch-up under the following conditions:

- A voltage higher than V_{CC} or lower than V_{SS} is applied to an input or output pin.
- A voltage higher than the rated voltage is applied between Vcc pins and Vss pins.
- The AV_{CC} power supply is applied before the V_{CC} voltage.

Latch-up may increase the power supply current dramatically, causing thermal damages to the device. For the same reason, extra care is required to not let the analog power-supply voltage (AV_{CC} , AVRH) exceed the digital power-supply voltage.

2. Unused pins handling

Unused input pins can be left open when the input is disabled (corresponding bit of Port Input Enable register PIER = 0).

Leaving unused input pins open when the input is enabled may result in misbehavior and possible permanent damage of the device. To prevent latch-up, they must therefore be pulled up or pulled down through resistors which should be more than $2k\Omega$.

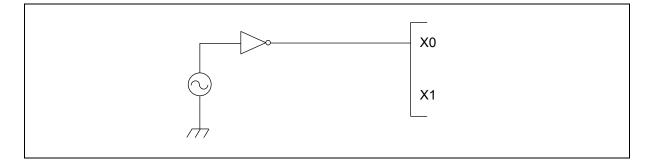
Unused bidirectional pins can be set either to the output state and be then left open, or to the input state with either input disabled or external pull-up/pull-down resistor as described above.

3. External clock usage

The permitted frequency range of an external clock depends on the oscillator type and configuration. See AC Characteristics for detailed modes and frequency limits. Single and opposite phase external clocks must be connected as follows:

(1) Single phase external clock for Main oscillator

When using a single phase external clock for the Main oscillator, X0 pin must be driven and X1 pin left open. And supply 1.8V power to the external clock.

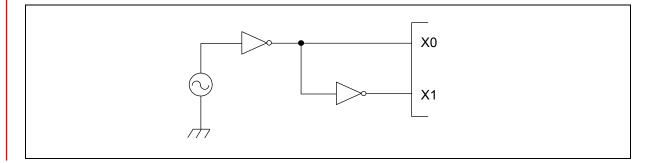


(2) Single phase external clock for Sub oscillator

When using a single phase external clock for the Sub oscillator, "External clock mode" must be selected and X0A/P04_0 pin must be driven. X1A/P04_1 pin can be configured as GPIO.

(3) Opposite phase external clock

When using an opposite phase external clock, X1 (X1A) pins must be supplied with a clock signal which has the opposite phase to the X0 (X0A) pins. Supply level on X0 and X1 pins must be 1.8V.



4. Notes on PLL clock mode operation

If the microcontroller is operated with PLL clock mode and no external oscillator is operating or no external clock is supplied, the microcontroller attempts to work with the free oscillating PLL. Performance of this operation, however, cannot be guaranteed.

5. Power supply pins (Vcc/Vss)

It is required that all V_{CC} -level as well as all V_{SS} -level power supply pins are at the same potential. If there is more than one V_{CC} or V_{SS} level, the device may operate incorrectly or be damaged even within the guaranteed operating range.

Vcc and Vss pins must be connected to the device from the power supply with lowest possible impedance. The smoothing capacitor at Vcc pin must use the one of a capacity value that is larger than Cs.

Besides this, as a measure against power supply noise, it is required to connect a bypass capacitor of about 0.1μ F between Vcc and Vss pins as close as possible to Vcc and Vss pins.

6. Crystal oscillator and ceramic resonator circuit

Noise at X0, X1 pins or X0A, X1A pins might cause abnormal operation. It is required to provide bypass capacitors with shortest possible distance to X0, X1 pins and X0A, X1A pins, crystal oscillator (or ceramic resonator) and ground lines, and, to the utmost effort, that the lines of oscillation circuit do not cross the lines of other circuits.

It is highly recommended to provide a printed circuit board art work surrounding X0, X1 pins and X0A, X1A pins with a ground area for stabilizing the operation.

It is highly recommended to evaluate the quartz/MCU or resonator/MCU system at the quartz or resonator manufacturer, especially when using low-Q resonators at higher frequencies.

7. Turn on sequence of power supply to A/D converter and analog inputs

It is required to turn the A/D converter power supply (AV_{CC}, AVRH, AVRL) and analog inputs (ANn) on after turning the digital power supply (V_{CC}) on.

It is also required to turn the digital power off after turning the A/D converter supply and analog inputs off. In this case, AVRH must not exceed AV_{CC} . Input voltage for ports shared with analog input ports also must not exceed AV_{CC} (turning the analog and digital power supplies simultaneously on or off is acceptable).

8. Pin handling when not using the A/D converter

If the A/D converter is not used, the power supply pins for A/D converter should be connected such as $AV_{CC} = V_{CC}$, $AV_{SS} = AVRH = AVRL = V_{SS}$.



9. Notes on Power-on

To prevent malfunction of the internal voltage regulator, supply voltage profile while turning the power supply on should be slower than $50\mu s$ from 0.2V to 2.7V.

10. Stabilization of power supply voltage

If the power supply voltage varies acutely even within the operation safety range of the V_{CC} power supply voltage, a malfunction may occur. The V_{CC} power supply voltage must therefore be stabilized. As stabilization guidelines, the power supply voltage must be stabilized in such a way that V_{CC} ripple fluctuations (peak to peak value) in the commercial frequencies (50Hz to 60Hz) fall within 10% of the standard V_{CC} power supply voltage and the transient fluctuation rate becomes 0.1V/µs or less in instantaneous fluctuation for power supply switching.

11. Serial communication

There is a possibility to receive wrong data due to noise or other causes on the serial communication. Therefore, design a printed circuit board so as to avoid noise.

Consider receiving of wrong data when designing the system. For example apply a checksum and retransmit the data if an error occurs.

12. Mode Pin (MD)

Connect the mode pin directly to Vcc or Vss pin. To prevent the device unintentionally entering test mode due to noise, lay out the printed circuit board so as to minimize the distance from the mode pin to Vcc or Vss pin and provide a low-impedance connection.

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ELECTRICAL CHARACTERISTICS

1. Absolute Maximum Ratings

$\begin{array}{ c c c c c c } \hline Parameter & Symbol & Condition & Rating & Uni \\ \hline Min & Max & Uni \\ \hline Max & Voltage*! & V_{CC} & - & V_{SS} - 0.3 & V_{SS} + 6.0 & V \\ \hline Analog power & AV_{CC} & - & V_{SS} - 0.3 & V_{SS} + 6.0 & V \\ \hline Analog reference & AVRH, & - & V_{SS} - 0.3 & V_{SS} + 6.0 & V \\ \hline Analog reference & AVRH, & - & V_{SS} - 0.3 & V_{SS} + 6.0 & V \\ \hline UCD power supply & V0 to V3 & - & V_{SS} - 0.3 & V_{SS} + 6.0 & V \\ \hline unut voltage*! & V_1 & - & V_{SS} - 0.3 & V_{SS} + 6.0 & V \\ \hline Output voltage*! & V_0 & - & V_{SS} - 0.3 & V_{SS} + 6.0 & V \\ \hline Maximum Clamp & I_{CLAMP} & - & -4.0 & +4.0 & mA \\ \hline Clamp Current & & Ul_{LCAMP} & - & -& 26 & mA \\ \hline TU' level maximum & & S I_{CLAMP} & - & -& 26 & mA \\ \hline TU' level maximum & & SI_{OL} & - & -& 15 & mA \\ \hline output current & & I_{OLAV} & - & -& 4 & mA \\ \hline output current & & SI_{OL} & - & -& 15 & mA \\ \hline unut current & & SI_{OL} & - & -& 15 & mA \\ \hline U'L' level maximum & & SI_{OL} & - & -& 15 & mA \\ \hline uutput current & & SI_{OLAV} & - & -& 32 & mA \\ \hline T'L' level maximum & & SI_{OL} & - & -& 100 & mA \\ \hline T'L' level maximum & & SI_{OL} & - & -& 15 & mA \\ \hline uutput current & & SI_{OLAV} & - & -& -& 100 & mA \\ \hline T'L' level maximum & & SI_{OL} & - & -& -100 & mA \\ \hline T'H' level maximum & & SI_{OHCO} & - & -& -15 & mA \\ \hline uutput current & & & SI_{OHCO} & - & -& -15 & mA \\ \hline T'H' level maximum & & SI_{OH} & - & -& -32 & mA \\ \hline uutput current & & & SI_{OHAV} & - & -& -32 & mA \\ \hline uutput current & & & SI_{OHAV} & - & -& -32 & mA \\ \hline uutput current & & & & SI_{OHAV} & - & -& -32 & mA \\ \hline U'H' level average & & & & & & & & & & & & & & & & & & &$	Dunch
voltage*1 V _{CC} - V _{SS} + 0.3 V _{SS} + 0.0 V Analog power supply voltage*1 AV _{CC} - V _{SS} - 0.3 V _{SS} + 6.0 V Analog reference voltage*1 AVRL - V _{SS} - 0.3 V _{SS} + 6.0 V LCD power supply voltage*1 V0 to V3 - V _{SS} - 0.3 V _{SS} + 6.0 V Input voltage*1 V1 - V _{SS} - 0.3 V _{SS} + 6.0 V Output voltage*1 V0 V0 - V _{SS} - 0.3 V _{SS} + 6.0 V Maximum Clamp I _{CLAMP} - V _{SS} - 0.3 V _{SS} + 6.0 V Maximum Clamp I _{CLAMP} - V _{SS} - 0.3 V _{SS} + 6.0 V Maximum Clamp I _{CLAMP} - - 2.6 mA "L" level maximum output current I _{OL} - - 2.6 mA "L" level average overall output I _{OLAV} - - 4 mA Unterent I _{OLAV} - - 15.0	Remarks
supply voltage*1 AV _{CC} - $V_{SS} = 0.3$ $V_{SS} = 0.0$ V Analog reference voltage*1 AVRH, AVRL - $V_{SS} = 0.3$ $V_{SS} + 6.0$ V LCD power supply voltage*1 V0 to V3 - $V_{SS} = 0.3$ $V_{SS} + 6.0$ V Input voltage*1 V_1 - $V_{SS} = 0.3$ $V_{SS} + 6.0$ V Output voltage*1 V_0 - $V_{SS} = 0.3$ $V_{SS} + 6.0$ V Maximum Clamp Current I_{CLAMP} - 4.0 $+4.0$ mA Total Maximum Clamp Current $\Sigma I_{CLAMP} $ - - 26 mA "L" level maximum output current I_{OL} - - 20 mA "L" level average overall output current I_{OLAV} - - 4 mA "L" level average overall output ΣI_{OLAV} - - 32 mA "L" level average overall output ΣI_{OLAV} - - 32 mA "L" level average overall o	
voltage*1 AVRL - $V_{SS} - 0.3$ $V_{SS} + 6.0$ V LCD power supply voltage*1 V0 to V3 - $V_{SS} - 0.3$ $V_{SS} + 6.0$ V Input voltage*1 V1 - $V_{SS} - 0.3$ $V_{SS} + 6.0$ V Output voltage*1 V0 - $V_{SS} - 0.3$ $V_{SS} + 6.0$ V Maximum Clamp I_{CLAMP} - -4.0 $+4.0$ mA Total Maximum I_{CLAMP} - -4.0 $+4.0$ mA "L" level maximum I_{OL} - - 26 mA "L" level average I_{OLAV} - - 20 mA utput current I_{OLAV} - - 4 mA verall output ΣI_{OL} - - 64 mA utput current $\SigmaI_{OLAVHCO}$ - - 150 mA "L" level maximum $\SigmaI_{OLAVHCO}$ - - 100 mA "L" level maxi	$V_{\rm CC} = A V_{\rm CC} *^2$
voltage*1 V0 to V3 - Vss - 0.3 Vss + 6.0 V Input voltage*1 V1 - Vss - 0.3 Vss + 6.0 V Output voltage*1 V0 - Vss - 0.3 Vss + 6.0 V Maximum Clamp Current IcLAMP - Vss - 0.3 Vss + 6.0 V Maximum Clamp Current IcLAMP - Vss - 0.3 Vss + 6.0 V Total Maximum Clamp Current IcLAMP - -4.0 +4.0 mA Total Maximum Clamp Current IoL - - 26 mA "L" level maximum output current IoLAV - - 20 mA "L" level average overall output current IoLAV - - 4 mA TU' level average overall output SIoLAV - - 150 mA "L" level average overall output SIoLAV - - 32 mA "H" level average overall output IoHAV - - -150 mA <t< td=""><td>$\label{eq:average} \begin{array}{l} AV_{CC} \geq AVRH, \\ AV_{CC} \geq AVRL, \\ AVRH > AVRL, \\ AVRL \geq AV_{SS} \end{array}$</td></t<>	$\label{eq:average} \begin{array}{l} AV_{CC} \geq AVRH, \\ AV_{CC} \geq AVRL, \\ AVRH > AVRL, \\ AVRL \geq AV_{SS} \end{array}$
Output voltage*1 V_0 - $V_{SS} - 0.3$ $V_{SS} + 6.0$ VMaximum Clamp Current I_{CLAMP} 4.0+4.0mATotal Maximum Clamp Current $\Sigma I_{CLAMP} $ 26mA"L" level maximum output current I_{OL} 15mA"L" level average output current I_{OLAV} 4mA"L" level average output current I_{OLAV} 4mA"L" level maximum overall output current ΣI_{OLAV} 64mA"L" level average overall output ΣI_{OLAV} 150mA"L" level maximum output current ΣI_{OLAV} 150mA"L" level average overall output ΣI_{OLAV} 100mA"H" level average output current ΣI_{OLAV} 150mA"H" level maximum output current I_{OH} 100mA"H" level maximum output current I_{OHAV} "H" level maximum overall output ΣI_{OH} "H" level average output I_{OHAV} "H" level average output ΣI_{OHAV} "H" level average output I_{OHAV}	V0 to V3 must not exceed V _{CC}
Maximum Clamp Current I_{CLAMP} 4.0+4.0mATotal Maximum Clamp Current $\Sigma I_{CLAMP} $ 26mA"L" level maximum output current I_{OL} 15mA"L" level average output current I_{OLAV} 4mA"L" level average output current I_{OLAV} 4mA"L" level maximum overall output current ΣI_{OLAV} 64mA"L" level average overall output ΣI_{OLAV} 150mA"L" level average overall output ΣI_{OLAV} 150mA"L" level average overall output ΣI_{OLAV} 150mA"H" level average output current ΣI_{OLAV} 32mA"H" level maximum output current I_{OH} "H" level maximum overall output ΣI_{OLAV} "H" level maximum overall output ΣI_{OH} "H" level average overall output ΣI_{OH} "H" level average overall output ΣI_{OHAV} "H" level average overall output ΣI_{OHAV}	$V_{I} \le V_{CC} + 0.3 V^{*3}$
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	$V_0 \le V_{CC} + 0.3V^{*3}$
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Applicable to general purpose I/O pins * ⁴
output current I_{OLHCO} 20mA"L" level average output current I_{OLAV} 4mA"L" level maximum overall output current ΣI_{OL} 15mA"L" level maximum overall output current ΣI_{OLAV} 64mA"L" level average overall output current ΣI_{OLHCO} 150mA"L" level average overall output current ΣI_{OLAV} 32mA"H" level maximum output current I_{OH} 100mA"H" level average output current I_{OHAV} "H" level maximum overall output ΣI_{OHAV} "H" level average overall output ΣI_{OHAV} "H" level average overall output ΣI_{OHAV} "H" level average overall output ΣI_{OHAV} <	Applicable to general purpose I/O pins * ⁴
"L" level average output current I_{OLAV} 4mA"L" level maximum overall output current ΣI_{OL} 15mA"L" level maximum overall output current ΣI_{OLHCO} 64mA"L" level average overall output current ΣI_{OLAV} 64mA"L" level average overall output current ΣI_{OLAV} 150mA"H" level maximum output current I_{OH} 100mA"H" level average output current I_{OHAV} 15mA"H" level maximum overall output current ΣI_{OHAV} "H" level average overall output current ΣI_{OHAV} "H" level average overall output ΣI_{OHAV} <td>Normal port</td>	Normal port
output currentI IOLAVHCO15mA"L" level maximum overall output current ΣI_{OL} 64mA"L" level average overall output current ΣI_{OLAV} 150mA"L" level average overall output current ΣI_{OLAV} 32mA"H" level maximum output current I_{OH} 100mA"H" level average output current I_{OHAV} 15mA"H" level average output current I_{OHAV} 4mA"H" level maximum overall output current ΣI_{OHAV} 4mA"H" level average overall output ΣI_{OH} 64mA"H" level average overall output ΣI_{OHAV} 150mA"H" level average overall output ΣI_{OHAV} "H" level average overall output ΣI_{OHAV} "H" level average overall output ΣI_{OHAV} "H" level average overall output ΣI_{OHAV}	High current port
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Normal port
overall output current ΣI_{OL} $ -$ <td>High current port</td>	High current port
current ΣI_{OLHCO} 150mA"L" level average overall output current ΣI_{OLAV} 32mA"H" level maximum output current I_{OH} 100mA"H" level average output current I_{OHHCO} 100mA"H" level average output current I_{OHAV} 15mA"H" level average output current I_{OHAV} 4mA"H" level maximum overall output current ΣI_{OH} 64mA"H" level average overall output ΣI_{OHHCO} 64mA"H" level average overall output ΣI_{OHAV} "H" level average overall output ΣI_{OHAV}	Normal port
overall output current ΣI_{OLAV} I I 32 $IIAX$ "H" level maximum output current I_{OH} 100mA"H" level maximum output current I_{OH} 15mA"H" level average output current I_{OHAV} 20mA"H" level maximum overall output current ΣI_{OHAV} 4mA"H" level maximum overall output ΣI_{OH} 64mA"H" level average overall output ΣI_{OHHCO} 150mA"H" level average overall output ΣI_{OHAV} 32mA	High current port
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Normal port
output currentI I OHACO20mA"H" level average output currentI OHAV4mA"H" level maximum overall output current ΣI_{OH} 15mA"H" level maximum overall output current ΣI_{OH} 64mA"H" level average overall output ΣI_{OHHCO} 150mA	High current port
"H" level average output current I_{OHAV} 4mA"H" level maximum overall output current ΣI_{OH} 4mA"H" level maximum overall output current ΣI_{OH} 64mA"H" level average overall output ΣI_{OHAV} 64mA	Normal port
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	High current port
output current $I_{OHAVHCO}$ 15mA"H" level maximum overall output current ΣI_{OH} 64mA"H" level average overall output ΣI_{OHHCO} 150mA"H" level average overall output ΣI_{OHAV} 32mA	Normal port
"H" level maximum overall output current ΣI_{OH} 64mA ΣI_{OHHCO} 150mA"H" level average overall output ΣI_{OHAV} 32mA	High current port
current ΣI_{OHHCO} 150mA"H" level average overall output ΣI_{OHAV} 32mA	
"H" level average overall output ΣI_{OHAV} 32mA	High current port
	Normal port
	High current port
Power consumption*5 P_D $T_A = +125^{\circ}C$ - 416^{*6} mW	
Operating ambient temperature T_A 40+125*7°C	
Storage temperature T_{STG} 55 +150 °C	

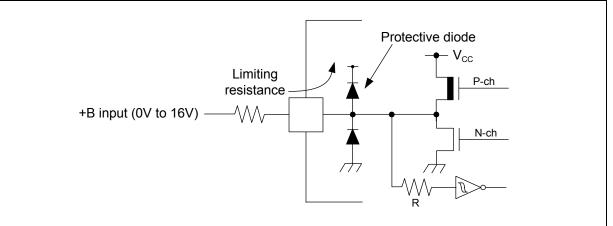
*1: This parameter is based on $V_{SS} = AV_{SS} = 0V$.

*2: AV_{CC} and V_{CC} must be set to the same voltage. It is required that AV_{CC} does not exceed V_{CC} and that the voltage at the analog inputs does not exceed AV_{CC} when the power is switched on.

*3: V₁ and V₀ should not exceed V_{CC} + 0.3V. V₁ should also not exceed the specified ratings. However if the maximum current to/from an input is limited by some means with external components, the I_{CLAMP} rating supersedes the V₁ rating. Input/Output voltages of general I/O ports depend on V_{CC}.

- *4: Applicable to all general purpose I/O pins (Pnn_m).
 - Use within recommended operating conditions.
 - Use at DC voltage (current).
 - The +B signal should always be applied a limiting resistance placed between the +B signal and the microcontroller.
 - The value of the limiting resistance should be set so that when the +B signal is applied the input current to the microcontroller pin does not exceed rated values, either instantaneously or for prolonged periods.
 - Note that when the microcontroller drive current is low, such as in the power saving modes, the +B input potential may pass through the protective diode and increase the potential at the V_{CC} pin, and this may affect other devices.
 - Note that if a +B signal is input when the microcontroller power supply is off (not fixed at 0V), the power supply is provided from the pins, so that incomplete operation may result.
 - Note that if the +B input is applied during power-on, the power supply is provided from the pins and the resulting supply voltage may not be sufficient to operate the Power reset.
 - The DEBUG I/F pin has only a protective diode against V_{SS}. Hence it is only permitted to input a negative clamping current (4mA). For protection against positive input voltages, use an external clamping diode which limits the input voltage to maximum 6.0V.

• Sample recommended circuits:



*5: The maximum permitted power dissipation depends on the ambient temperature, the air flow velocity and the thermal conductance of the package on the PCB.

The actual power dissipation depends on the customer application and can be calculated as follows: $P_D = P_{IO} + P_{INT}$

 $P_{IO} = \Sigma (V_{OL} \times I_{OL} + V_{OH} \times I_{OH})$ (I/O load power dissipation, sum is performed on all I/O ports) $P_{INT} = V_{CC} \times (I_{CC} + I_A)$ (internal power dissipation)

 I_{CC} is the total core current consumption into V_{CC} as described in the "DC characteristics" and depends on the selected operation mode and clock frequency and the usage of functions like Flash programming.

 I_A is the analog current consumption into AV_{CC} .

*6: Worst case value for a package mounted on single layer PCB at specified T_A without air flow.

*7: Write/erase to a large sector in flash memory is warranted with $T_A \le +105^{\circ}C$.

<WARNING>

Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

	-	•				$(V_{SS} = AV_{SS} = 0V)$
Parameter	Symbol	Value			Unit	Remarks
Falametei	Symbol	Min	Тур	Max	Unit	Remarks
Power supply	V_{CC} , AV_{CC}	2.7	-	5.5	V	
voltage	V _{CC} , AV _{CC}	2.0	-	5.5	V	Maintains RAM data in stop mode
Smoothing capacitor at C pin	Cs	0.5	1.0 to 3.9	4.7	μF	1.0 μ F (Allowance within ± 50%) 3.9 μ F (Allowance within ± 20%) Please use the ceramic capacitor or the capacitor of the frequency response of this level. The smoothing capacitor at V _{CC} must use the one of a capacity value that is larger than C _S .

2. Recommended Operating Conditions

<WARNING>

The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated within these ranges.

Always use semiconductor devices within their recommended operating condition ranges. Operation outside these ranges may adversely affect reliability and could result in device failure. No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their representatives beforehand.

3. DC Characteristics

(1) Current Rating

. ,	vaung		$(V_{CC} = AV_{CC} = 2.7V \text{ to } 5$.5V, Vs		s = 0V, T	$A = -40^{\circ}$	°C to + 125°C)																							
Parameter	Symbol	Pin	Conditions	Min	Value	Max	Unit	Remarks																							
		name	PLL Run mode with CLKS1/2 = CLKB =	-	Тур 28	-	mA	$T_A = +25^{\circ}C$																							
	I _{CCPLL}		CLKP1/2 = 32MHz Flash 0 wait	-	-	38	mA	$T_{A} = +105^{\circ}C$																							
				(CLKRC and CLKSC stopped)	-	-	39.5	mA	$T_{A} = +125^{\circ}C$																						
			Main Run mode with CLKS1/2 = CLKB = CLKP1/2 = 4MHz	-	3.5	-	mA	$T_A = +25^{\circ}C$																							
	I _{CCMAIN}		Flash 0 wait	-	-	8	mA	$T_{A} = +105^{\circ}C$																							
			(CLKPLL, CLKSC and CLKRC stopped)	-	-	9.5	mA	$T_A = +125^{\circ}C$																							
	I _{CCRCH} Vec		RC Run mode with CLKS1/2 = CLKB = CLKP1/2 = CLKRC =	-	1.8	-	mA	$T_A = +25^{\circ}C$																							
Power supply current in Run modes ^{*1}		Vcc	2MHz Flash 0 wait	-	-	6	mA	$T_{A} = +105^{\circ}C$																							
modes			(CLKMC, CLKPLL and CLKSC stopped)	-	-	7.5	mA	$T_{A} = +125^{\circ}C$																							
			RC Run mode with CLKS1/2 = CLKB = CLKP1/2 = CLKRC =	-	0.16	-	mA	$T_A = +25^{\circ}C$																							
					_	-														100kHz Flash 0 wait	-	-	3.5	mA	$T_{A} = +105^{\circ}C$						
							(CLKMC, CLKPLL and CLKSC stopped)	-	-	5	mA	$T_{A} = +125^{\circ}C$																			
	I _{CCSUB}										_			_		_			_		-					Sub Run mode with CLKS1/2 = CLKB = CLKP1/2 = 32kHz	-	0.1	-	mA	$T_A = +25^{\circ}C$
																													CLKP1/2 = 32kHz Flash 0 wait	-	-
			(CLKMC, CLKPLL and CLKRC stopped)	-	-	4.8	mA	$T_{A} = +125^{\circ}C$																							

Deremeter	Cumbal	Pin	Conditions		Value		Linit	Remarks	
Parameter	Symbol	name	Conditions	Min	Тур	Max	Unit	Remarks	
			PLL Sleep mode with	-	9.5	-	mA	$T_A = +25^{\circ}C$	
	I _{CCSPLL}		CLKS1/2 = CLKP1/2 = 32MHz	-	-	15	mA	$T_{A} = +105^{\circ}C$	
			(CLKRC and CLKSC stopped)	-	-	16.5	mA	$T_{A} = +125^{\circ}C$	
CLKS1/2	Main Sleep mode with CLKS1/2 = CLKP1/2 =	-	1.1	-	mA	$T_A = +25^{\circ}C$			
	I _{CCSMAIN}		4MHz, SMCR:LPMSS = 0 (CLKPLL, CLKRC	-	-	4.7	mA	$T_{A} = +105^{\circ}C$	
		(CLKPLL, CLKRC and CLKSC stopped)	-	-	6.2	mA	$T_{A} = +125^{\circ}C$		
		1	RC Sleep mode with CLKS1/2 = CLKP1/2 =	-	0.6	-	mA	$T_A = +25^{\circ}C$	
Power supply current in	I _{CCSRCH} V	Vcc	Vcc CLKRC = 2MHz, SMCR:LPMSS = 0 (CLKMC, CLKPLL and CLKSC stopped)	-	-	4.1	mA	$T_{A} = +105^{\circ}C$	
Sleep modes ^{*1}				-	-	5.6	mA	$T_{A} = +125^{\circ}C$	
			RC Sleep mode with	-	0.07	-	mA	$T_A = +25^{\circ}C$	
	I _{CCSRCL}		CLKS1/2 = CLKP1/2 = CLKRC = 100kHz (CLKMC, CLKPLL	-	-	2.9	mA	$T_{A} = +105^{\circ}C$	
			and CLKSC stopped)	-	-	4.4	mA	$T_{A} = +125^{\circ}C$	
	I _{CCSSUB}		Sub Sleep mode with	-	0.04	-	mA	$T_A = +25^{\circ}C$	
			CLKS1/2 = CLKP1/2 = 32kHz, (CLKMC, CLKPLL	-	-	2.7	mA	$T_{A} = +105^{\circ}C$	
			and CLKRC stopped)	-	-	4.2	mA	$T_{A} = +125^{\circ}C$	

Parameter	Symbol	Pin	Conditions		Value		Unit	Remarks	
Falameter	Symbol	name	Conditions	Min	Тур	Max	Offic		
			PLL Timer mode with	-	1800	2250	μA	$T_A = +25^{\circ}C$	
	I _{CCTPLL}		CLKPLL = 32MHz (CLKRC	-	-	3220	μΑ	$T_{A} = +105^{\circ}C$	
			and CLKSC stopped)	-	-	4200	μΑ	$T_{A} = +125^{\circ}C$	
			Main Timer mode with CLKMC = 4MHz,	-	285	330	μΑ	$T_A = +25^{\circ}C$	
	I _{CCTMAIN}		SMCR:LPMSS = 0 (CLKPLL, CLKRC and	-	-	1200	μΑ	$T_{A} = +105^{\circ}C$	
Power			CLKSC stopped)	-	-	2155	μΑ	$T_{A} = +125^{\circ}C$	
			RC Timer mode with CLKRC = 2MHz, SMCR:LPMSS = 0 (CLKPLL, CLKMC and	-	160	215	μΑ	$T_A = +25^{\circ}C$	
supply current in	I _{CCTRCH}	Vcc		-	-	1110	μΑ	$T_{A} = +105^{\circ}C$	
Timer modes ^{*2}			CLKPLL, CLKMC and CLKSC stopped)	-	-	2065	μΑ	$T_{A} = +125^{\circ}C$	
			RC Timer mode with	-	35	75	μΑ	$T_A = +25^{\circ}C$	
	I _{CCTRCL}		CLKRC = 100kHz, (CLKPLL, CLKMC and	-	-	910	μΑ	$T_{A} = +105^{\circ}C$	
I			CLKSC stopped)	-	-	1870	μΑ	$T_{A} = +125^{\circ}C$	
	I _{CCTSUB}		Sub Timer mode with CLKSC = 32kHz (CLKMC, CLKPLL and	-	25	65	μΑ	$T_A = +25^{\circ}C$	
				-	-	885	μΑ	$T_{A} = +105^{\circ}C$	
			CLKRC stopped)	-	-	1845	μΑ	$T_{A} = +125^{\circ}C$	

Parameter	Symbol	Pin	Pin Conditions		Value			Remarks
Falametei	Symbol	name	Conditions	Min	Тур	Max	Unit	Remarks
Power supply				-	20	60	μΑ	$T_A = +25^{\circ}C$
current in Stop mode ^{*3}	I _{CCH}		-	-	-	880	μΑ	$T_A = +105^{\circ}C$
				-	-	1840	μΑ	$T_A = +125^{\circ}C$
Flash Power Down current	I _{CCFLASHPD}		-	-	36	70	μΑ	
Power supply current for active Low	I _{CCLVD}	Vcc	Low voltage	-	5	-	μΑ	$T_A = +25^{\circ}C$
Voltage detector ^{*4}	ICCLVD		detector enabled	-	-	12.5	μΑ	$T_{A} = +125^{\circ}C$
Flash Write/	I _{CCFLASH}		_	-	12.5	-	mA	$T_A = +25^{\circ}C$
Erase current* ⁵	-CCFLASH			-	-	20	mA	$T_{A} = +125^{\circ}C$

*1: The power supply current is measured with a 4MHz external clock connected to the Main oscillator and a 32kHz external clock connected to the Sub oscillator. See chapter "Standby mode and voltage regulator control circuit" of the Hardware Manual for further details about voltage regulator control. Current for "On Chip Debugger" part is not included. Power supply current in Run mode does not include Flash Write / Erase current.

- *2: The power supply current in Timer mode is the value when Flash is in Power-down / reset mode. When Flash is not in Power-down / reset mode, I_{CCFLASHPD} must be added to the Power supply current. The power supply current is measured with a 4MHz external clock connected to the Main oscillator and a 32kHz external clock connected to the Sub oscillator. The current for "On Chip Debugger" part is not included.
- *3: The power supply current in Stop mode is the value when Flash is in Power-down / reset mode. When Flash is not in Power-down / reset mode, I_{CCFLASHPD} must be added to the Power supply current.

*4: When low voltage detector is enabled, I_{CCLVD} must be added to Power supply current.

*5: When Flash Write / Erase program is executed, I_{CCFLASH} must be added to Power supply current.

(2) Pin Characteristics

$(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}C \text{ to } + 125^{\circ}C$								
Parameter	Symbol	Pin name	Conditions	Min	Typ	Max	Unit	Remarks
		Port inputs	-	$V_{CC} \times 0.7$	-	V_{CC} + 0.3	v	CMOS Hysteresis input
	V _{IH}	Pnn_m	-	$V_{CC} \times 0.8$	-	$V_{CC} + 0.3$	V	AUTOMOTIVE Hysteresis input
0770 1 1	V _{IHX0S}	X0	External clock in "Fast Clock Input mode"	VD × 0.8	-	VD	V	VD=1.8V±0.15V
"H" level input	V _{IHX0AS}	X0A	External clock in "Oscillation mode"	$V_{CC} \times 0.8$	-	V _{CC} + 0.3	V	
voltage	V _{IHR}	RSTX	-	$V_{CC} \times 0.8$	-	V _{CC} + 0.3	V	CMOS Hysteresis input
	V _{IHM}	MD	-	V _{CC} - 0.3	-	V _{CC} + 0.3	v	CMOS Hysteresis input
	V _{IHD}	DEBUG I/F	-	2.0	-	V _{CC} + 0.3	v	TTL Input
	V _{IL}	Port inputs	-	V _{SS} - 0.3	-	$V_{CC} \times 0.3$	v	CMOS Hysteresis input
	▼ IL	Pnn_m	-	V _{SS} - 0.3	-	$V_{CC} \times 0.5$	v	AUTOMOTIVE Hysteresis input
"I " level	V _{ILX0S}	X0	External clock in "Fast Clock Input mode"	V _{ss}	-	$VD \times 0.2$	v	VD=1.8V±0.15V
input	V _{ILX0AS}	X0A	External clock in "Oscillation mode"	V _{SS} - 0.3	-	$V_{CC} \times 0.2$	v	
voltage	V _{ILR}	RSTX	-	V _{SS} - 0.3	-	$V_{CC} \times 0.2$	v	CMOS Hysteresis input
	V _{ILM}	MD	-	V _{SS} - 0.3	-	V _{SS} + 0.3	v	CMOS Hysteresis input
	VILM MD VILD DEBUG I/F	-	V _{SS} - 0.3	-	0.8	v	TTL Input	
	V _{OH4}	4mA type	$4.5V \le V_{CC} \le 5.5V$ $I_{OH} = -4mA$ $2.7V \le V_{CC} < 4.5V$ $I_{OH} = -1.5mA$	V _{CC} - 0.5	-	V _{CC}	v	
"H" level output voltage	V _{OH20}	High Drive type [*]	$\begin{array}{c} 4.5V \leq V_{CC} \leq 5.5V \\ \hline I_{OH} = -20mA \\ \hline 2.7V \leq V_{CC} < 4.5V \\ \hline I_{OH} = -13mA \end{array}$	V _{CC} - 0.6	-	V _{CC}	v	
"L" level input voltage "H" level output	V _{OH3}	3mA type	$4.5V \le V_{CC} \le 5.5V$ $I_{OH} = -3mA$ $2.7V \le V_{CC} < 4.5V$ $I_{OH} = -1.5mA$	V _{CC} - 0.5	-	V _{CC}	v	
	V _{OL4}	4mA type		-	-	0.4	V	
output	V _{OL20}	High Drive type [*]	$\begin{array}{c} 4.5V \leq V_{CC} \leq 5.5V \\ I_{OL} = +20mA \\ 2.7V \leq V_{CC} < 4.5V \\ I_{OL} = +13mA \end{array}$	-	-	0.6	V	
output	V _{OL3}	3mA type	$2.7V \le V_{CC} < 5.5V$ $I_{OL} = +3mA$	-	-	0.4	V	
	V _{OLD}	DEBUG I/F	$V_{CC} = 2.7V$ $I_{OL} = +25mA$	0	-	0.25	v	



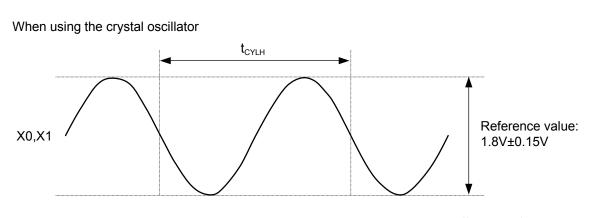
Parameter	Symbol	Din nomo	Conditions		Value		Unit	Remarks
Farameter	Symbol	Finname	Conditions	Min	Тур	Max	Unit	Remarks
Input leak	I _{IL}	Pnn_m	$\begin{array}{c} V_{SS} < V_{I} < V_{CC} \\ AV_{SS}, AVRL < V_{I} < \\ AV_{CC}, AVRH \end{array}$	- 1	-	+ 1	μΑ	Single port pin except high current output I/O
current	ΠL	P08_m, P09_m, P10_m	$\begin{array}{c} V_{SS} < V_{I} < V_{CC} \\ AV_{SS} AVRL < V_{I} < \\ AV_{CC} , AVRH \end{array}$	- 3	-	+ 3	μΑ	
Total LCD leak current	$\Sigma I_{ILCD} $	All SEG/ COM pin	$V_{CC} = 5.0 V$	-	0.5	10	μΑ	Maximum leakage current of all LCD pins
Internal LCD divide resistance	R _{LCD}	Between V3 and V2, V2 and V1, V1 and V0	$V_{CC} = 5.0 V$	6.25	12.5	25	kΩ	
Pull-up resistance value	R _{PU}	Pnn_m	$V_{CC} = 5.0V \pm 10\%$	25	50	100	kΩ	
Input capacitance	C _{IN}	Other than C, Vcc, Vss, AVcc, AVss, AVRH, AVRL, P08_m, P09_m, P10_m	-	-	5	15	pF	
		P08_m, P09_m, P10_m	-	-	15	30	pF	

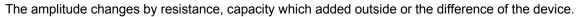
*: In the case of high current outputs, set "1" to the bit in the Port High Drive Register.

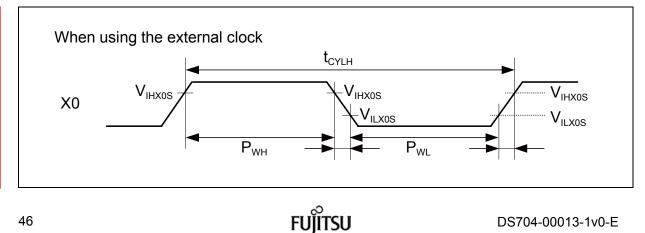
4. AC Characteristics

(1) Main Clock Input Characteristics

()	$V_{\rm CC} = AV_{\rm CC}$	= 2.7V to 5	.5V, VD=	1.8V±0.15	$5V, V_{SS} = 1$	$AV_{SS} = 0V$	$T_{\rm A} = -40^{\circ}{\rm C} \text{ to} + 125^{\circ}{\rm C}$
Parameter	Symbol	Pin		Value		Unit	Remarks
Falametei	Symbol	name	Min	Тур	Max	Unit	Remarks
			4	-	8	MHz	When using a crystal oscillator, PLL off
Input frequency	f _C	X0,	-	-	8	MHz	When using an opposite phase external clock, PLL off
input nequency		X1	4	-	8	MHz	When using a crystal oscillator or opposite phase external clock, PLL on
Input frequency	f _{FCI}	VO	-	-	8	MHz	When using a single phase external clock in "Fast Clock Input mode", PLL off
		X0	4	-	8	MHz	When using a single phase external clock in "Fast Clock Input mode", PLL on
Input clock cycle	$t_{\rm CYLH}$	-	125	-	-	ns	
Input clock pulse width	P _{WH} , P _{WL}	-	55	-	-	ns	



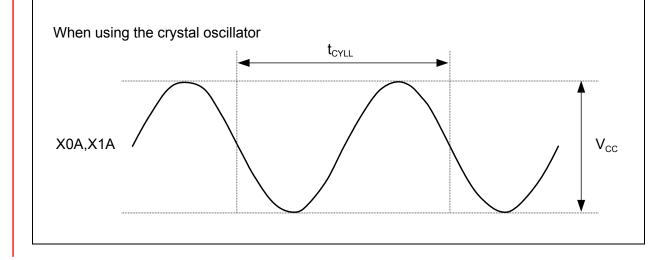


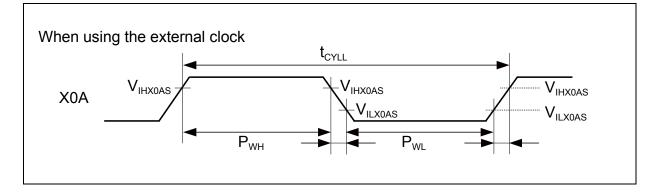


DS704-00013-1v0-E

	$(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}\text{C to} + 125^{\circ}\text{C}$											
Parameter	Symbol	Pin	Conditions		Value		Unit	Remarks				
Falametei	Symbol	name	Conditions	Min	Тур	Max	Unit	Remarks				
Input frequency		X0A,	-	-	32.768	-	kHz	When using an oscillation circuit				
	\mathbf{f}_{CL}	XIA XIA	-	-	-	100	kHz	When using an opposite phase external clock				
		X0A	-	-	-	50	kHz	When using a single phase external clock				
Input clock cycle	$t_{\rm CYLL}$	-	-	10	-	-	μs					
Input clock pulse width	-	-	$\begin{array}{l} P_{\rm WH}/t_{\rm CYLL},\\ P_{\rm WL}/t_{\rm CYLL} \end{array}$	30	-	70	%					

(2) Sub Clock Input Characteristics





		$(V_{CC} =$	$AV_{CC} = 2.7$	V to $5.5V$,	$V_{SS} = AV_S$	$T_{AS} = 0V, T_{A} = -40^{\circ}C \text{ to } + 125^{\circ}C)$
Parameter	Symbol		Value		Unit	Remarks
Farameter	Symbol	Min	Тур	Max	Onic	Remarks
Clock frequency	f	50	100	200	kHz	When using slow frequency of RC oscillator
Clock frequency	f_{RC}	1	2	4	MHz	When using fast frequency of RC oscillator
RC clock stabilization	4	80	160	320	μs	When using slow frequency of RC oscillator (16 RC clock cycles)
time	t _{rcstab}	64	128	256	μs	When using fast frequency of RC oscillator (256 RC clock cycles)

(3) Built-in RC Oscillation Characteristics

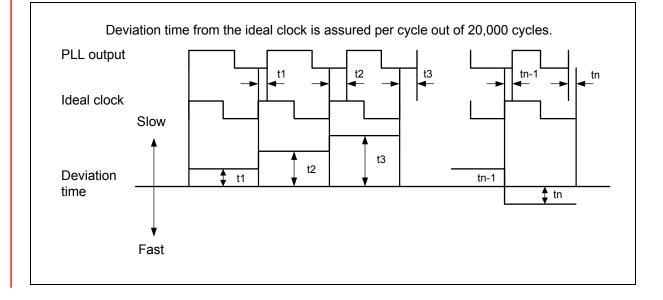
(4) Internal Clock Timing

$(V_{CC} = AV)$	$V_{\rm CC} = 2.7 \text{V} \text{ to } 5.5 \text{V}, \text{V}_{\rm SS} =$	$AV_{SS} = 0V, T$	$T_{\rm A} = -40^{\circ} {\rm C}$ to -	+ 125°C)
Parameter	Symbol	Va	Unit	
Falameter	Symbol	Min	Max	Unit
Internal System clock frequency (CLKS1 and CLKS2)	f_{CLKS1},f_{CLKS2}	-	54	MHz
Internal CPU clock frequency (CLKB), Internal peripheral clock frequency (CLKP1)	f _{CLKB} , f _{CLKP1}	-	32	MHz
Internal peripheral clock frequency (CLKP2)	f _{CLKP2}	-	32	MHz

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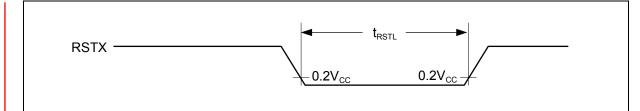
(5) Operating Conditions of PLL

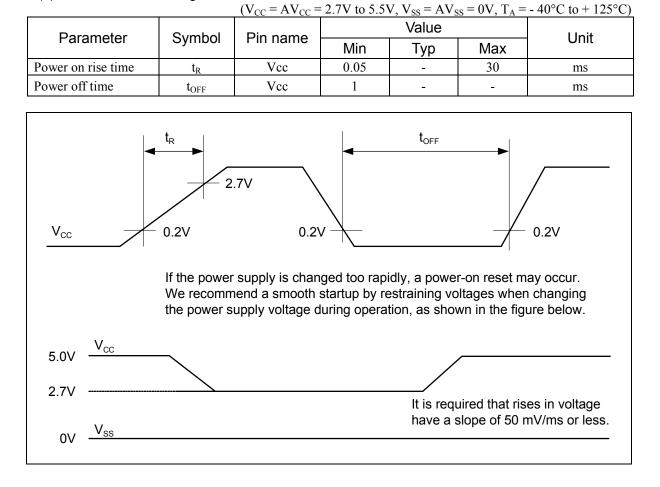
(V ₀	$_{\rm CC} = AV_{\rm CC} =$	= 2.7V 1	to 5.5V	$V_{SS} =$	$AV_{SS} = 0$	$V_{\rm A} = -40^{\circ}C \text{ to } + 125^{\circ}C$	
Parameter	Symbol	Value			Unit	Remarks	
Falanleter	Symbol	Min Typ Max		Unit	Remarks		
PLL oscillation stabilization wait time	t _{LOCK}	1	-	4	ms	For CLKMC = 4MHz	
PLL input clock frequency	f_{PLLI}	4	-	8	MHz		
PLL oscillation clock frequency	f _{CLKVCO}	56	-	108	MHz	Permitted VCO output frequency of PLL (CLKVCO)	
PLL phase jitter	t _{PSKEW}	-5	-	+5	ns	For CLKMC (PLL input clock) ≥ 4MHz	



(6) Reset Input

	$(V_{CC} = AV)$	$_{\rm CC} = 2.7 {\rm V}$ to 5.5	$SV, V_{SS} = AV_{SS}$	$= 0V, T_A = -40$	0° C to + 125°C)	
Parameter	Symbol	Pin name	Va	Unit		
Faranielei	Symbol	i in name	Min	Max	Onit	
Reset input time	+	DOTY	10	-	μs	
Rejection of reset input time	t _{RSTL}	RSTX	1	-	μs	
	1	1			· ·	





(7) Power-on Reset Timing

(8) USART Timing

(V	$V_{\rm CC} = AV_{\rm CC}$	= 2.7 V	to 5.5V, $V_{SS} =$	$AV_{SS} = 0V$	$T_{\rm A} = -40$	$^{\circ}$ C to + 125	5°C, C _L =5	0pF)
Parameter	Symbol	Pin	Conditions	$4.5V \le V_C$	_C < 5.5V	$2.7V \leq V_{C}$	_c < 4.5V	Unit
Farameter	Symbol	name	Conditions	Min	Max	Min	Max	Unit
Serial clock cycle time	t _{SCYC}	SCKn		4t _{CLKP1}	-	4t _{CLKP1}	-	ns
SCK $\downarrow \rightarrow$ SOT delay time	taroru	SCKn,		- 20	+20	- 30	+ 30	ns
	t _{SLOVI}	SOTn		- 20	+ 20	- 30	1 30	115
SOT \rightarrow SCK \uparrow delay time	t _{ovshi}	SCKn,	Internal shift	N×t _{CLKP1}	_	N×t _{CLKP1}	_	ns
Sol / Selk + delay time	UVSHI	SOTn	clock mode	-20^{*}	_	-30^{*}	_	115
SIN \rightarrow SCK \uparrow setup time	t _{IVSHI}	SCKn,	•••••••	t _{CLKP1}	_	t _{CLKP1}	_	ns
Shit y Serie + Setup time	417 2011	SINn		+ 45		+ 55		110
SCK $\uparrow \rightarrow$ SIN hold time	t _{SHIXI}	SCKn,		0	-	0	-	ns
	·SIIIAI	SINn				-		
Serial clock "L" pulse width	t _{SLSH}	SCKn		t _{CLKP1}	-	t _{CLKP1}	-	ns
-				+ 10		+ 10		
Serial clock "H" pulse width	t_{SHSL}	SCKn		t_{CLKP1}	-	t_{CLKP1}	-	ns
		SCKn,		+10	2+	+ 10	2+	
SCK $\downarrow \rightarrow$ SOT delay time	t _{SLOVE}	SOTn	External shift	-	$2t_{CLKP1}$ + 45	-	$2t_{CLKP1}$ + 55	ns
		SCKn,	clock mode	t _{CLKP1} /2	1 45	t _{CLKP1} /2	1 55	
SIN \rightarrow SCK \uparrow setup time	$t_{\rm IVSHE}$	SINn	clock mode	+10	-	+10	-	ns
<u>^</u>		SCKn,		t _{CLKP1}		t _{CLKP1}		
SCK $\uparrow \rightarrow$ SIN hold time	$t_{\rm SHIXE}$	SINn		+10	-	+10	-	ns
SCK fall time	t _F	SCKn		-	20	-	20	ns
SCK rise time	t _R	SCKn		-	20	-	20	ns

Notes: • AC characteristic in CLK synchronized mode.

 \bullet $C_{\rm L}$ is the load capacity value of pins when testing.

• Depending on the used machine clock frequency, the maximum possible baud rate can be limited by some parameters. These parameters are shown in "MB96600 series HARDWARE MANUAL".

• t_{CLKP1} indicates the peripheral clock 1 (CLKP1), Unit: ns

• These characteristics only guarantee the same relocate port number.

For example, the combination of SCKn and SOTn_R is not guaranteed.

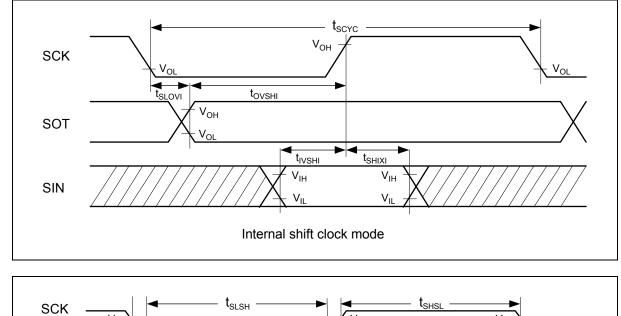
*: Parameter N depends on t_{SCYC} and can be calculated as follows:

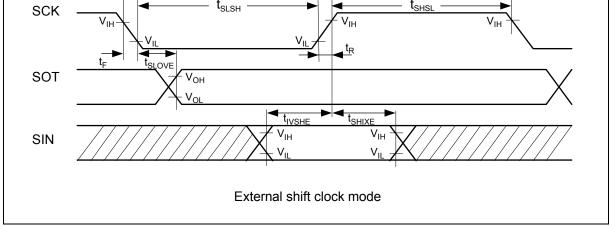
• If $t_{SCYC} = 2 \times k \times t_{CLKP1}$, then N = k, where k is an integer > 2

• If $t_{SCYC} = (2 \times k + 1) \times t_{CLKP1}$, then N = k + 1, where k is an integer > 1

Examples:

t _{SCYC}	Ν
$4 \times t_{CLKP1}$	2
$5 \times t_{CLKP1}, 6 \times t_{CLKP1}$	3
$7 \times t_{\text{CLKP1}}, 8 \times t_{\text{CLKP1}}$	4





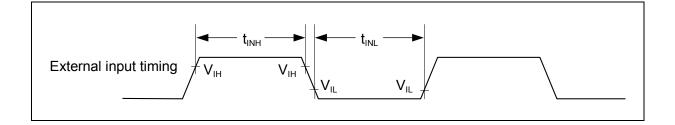
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(9) External Input Timing

		$(V_{CC} = AV_{CC})$	= 2.7 V to 5.5 V, V	$V_{\rm SS} = AV$	$V_{\rm SS} = 0V$	$T_{\rm A} = -40^{\circ}{\rm C} \text{ to } + 125^{\circ}{\rm C}$		
Parameter	Symbol	Pin name	Value		Unit	Remarks		
Falametei	Symbol	Fill Hallie	Min		Onit	Remains		
		Pnn_m				General Purpose I/O		
	t _{INH} ,	ADTG			A/D Converter trigger input			
		TINn				Reload Timer		
		$\begin{array}{c c} \hline TTGn & 2t_{CLKP1}+200 \\ \hline FRCKn, & (t_{CLKP1}= \\ FRCKn_R & 1/f_{CLKP1})^* \end{array}$		TTGn	$2t_{CLKP1} + 200$			PPG trigger input
			-	ns	Free-Running Timer			
Innut nulse width			EDCV = D = 1/C			input clock		
Input pulse width	t _{INL}	INn, INn_R				Input Capture		
		AINn, BINn,				Quadrature		
					Position/Revolution			
		ZINn				Counter		
		INTn, INTn_R				External Interrupt		
		NMI	200	-	ns	Non-Maskable		
		1 11111				Interrupt		

*: t_{CLKP1} indicates the peripheral clock1 (CLKP1) cycle time except stop when in stop mode.



(10) I²C Timing

	(V_{CO})	$_{\rm C} = {\rm AV}_{\rm CC} = 2.7 {\rm V} {\rm to}$	o 5.5V, V _S	$s = AV_{SS} =$	$0V, T_A = -$	-40° C to +	125°C)
Parameter	Symbol	Conditions	Typica	l mode	High- mo	Unit	
			Min	Max	Min	Max	
SCL clock frequency	f _{SCL}		0	100	0	400	kHz
(Repeated) START condition							
hold time	t _{HDSTA}		4.0	-	0.6	-	μs
$SDA \downarrow \rightarrow SCL \downarrow$							
SCL clock "L" width	t _{LOW}		4.7	-	1.3	-	μs
SCL clock "H" width	t _{HIGH}		4.0	-	0.6	-	μs
(Repeated) START condition							
setup time	t _{SUSTA}		4.7	-	0.6	-	μs
$\operatorname{SCL} \uparrow \to \operatorname{SDA} \downarrow$		$C_L = 50 pF$,					
Data hold time	t _{HDDAT}	$R = (Vp/I_{OL})^{*1}$	0	3.45^{*2}	0	0.9^{*^3}	μs
$\operatorname{SCL} \downarrow \to \operatorname{SDA} \downarrow \uparrow$	HDDAI		0	5.45	0	0.9	μs
Data setup time	t _{SUDAT}		250	_	100	_	ns
$SDA \downarrow \uparrow \rightarrow SCL \uparrow$	SUDAI		230		100		115
STOP condition setup time	t _{susto}		4.0	_	0.6	_	μs
$\operatorname{SCL} \uparrow \to \operatorname{SDA} \uparrow$	\$0510		1.0		0.0		μο
Bus free time between							
"STOP condition" and	t _{BUS}		4.7	-	1.3	-	μs
"START condition"							
Pulse width of spikes which			_	(1-1.5) ×		(1-1.5) ×	
will be suppressed by input	t _{SP}	-	0	t_{CLKP1}^{*5}	0	t_{CLKP1}^{*5}	ns
noise filter				·CLKFI		·CLKF1	

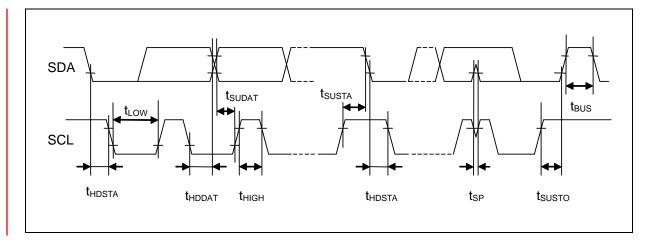
*1: R and C_L represent the pull-up resistance and load capacitance of the SCL and SDA lines, respectively. Vp indicates the power supply voltage of the pull-up resistance and IoL indicates VoL guaranteed current.

*2: The maximum t_{HDDAT} only has to be met if the device does not extend the "L" width (t_{LOW}) of the SCL signal.

*3: A high-speed mode I²C bus device can be used on a standard mode I²C bus system as long as the device satisfies the requirement of " $t_{SUDAT} \ge 250$ ns".

*4: For use at over 100kHz, set the peripheral clock1 (CLKP1) to at least 6MHz.

*5: t_{CLKP1} indicates the peripheral clock1 (CLKP1) cycle time.



5. A/D Converter

(1) Electrical Characteristics for the A/D Converter

	0	Pin		Value			$F_{A} = -40^{\circ}C \text{ to} + 125^{\circ}C)$
Parameter	Symbol	name	Min	Тур	Max	Unit	Remarks
Resolution	-	-	-	-	10	bit	
Total error	-	-	- 3.0	-	+ 3.0	LSB	
Nonlinearity error	-	-	- 2.5	-	+ 2.5	LSB	
Differential Nonlinearity error	-	-	- 1.9	-	+ 1.9	LSB	
Zero transition voltage	V _{OT}	ANn	Тур - 20	AVRL + 0.5LSB	Typ + 20	mV	
Full scale transition voltage	V _{FST}	ANn	Тур - 20	AVRH - 1.5LSB	Typ + 20	mV	
Compare time [*]	-	_	1.0	-	5.0	μs	$4.5V \leq AV_{CC} \leq 5.5V$
compare unic	_	_	2.2	-	8.0	μs	$2.7V \le AV_{CC} < 4.5V$
Sampling time [*]	-	_	0.5	-	-	μs	$4.5V \leq AV_{CC} \leq 5.5V$
Sampling time			1.2	-	-	μs	$2.7V \le AV_{CC} < 4.5V$
Power supply	I _A		-	2.0	3.1	mA	A/D Converter active
current	I _{AH}	AV _{CC}	-	-	3.3	μΑ	A/D Converter not operated
Reference power supply current	I _R	AVRH	-	520	810	μΑ	A/D Converter active
(between AVRH and AVRL)	I_{RH}	Ανκη	-	-	1.0	μΑ	A/D Converter not operated
Analog input capacity	C _{VIN}	AN2 to 4, 6 to 8, 10 to 12, 14, 15	-	-	16.0	pF	Normal outputs
		AN16 to 31	-	-	17.8	pF	High current outputs
Analog impedance	R _{VIN}	ANn	-	-	2050	Ω	$4.5V \le AV_{CC} \le 5.5V$
Analog impedance	KVIN		-	-	3600	Ω	$2.7V \leq AV_{CC} < 4.5V$
Analog port input current (during conversion)	I _{AIN}	AN2 to 4, 6 to 8, 10 to 12, 14, 15	- 0.3	-	+ 0.3	μΑ	AV _{SS} , AVRL < V _{AIN} < AV _{CC} , AVRH
		AN16 to 31	- 3.0	-	+ 3.0	μA]
Analog input voltage	V _{AIN}	ANn	AVRL	-	AVRH	V	
Reference voltage	-	AVRH	AV _{CC} - 0.1	-	AV _{CC}	V	
range	-	AVRL	AV _{SS}	-	AV _{SS} + 0.1	V	
Variation between channels	-	ANn	-	-	4.0	LSB	

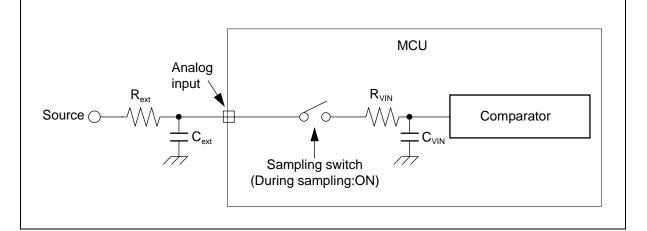
*: Time for each channel.

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(2) Accuracy and Setting of the A/D Converter Sampling Time

If the external impedance is too high or the sampling time too short, the analog voltage charged to the internal sample and hold capacitor is insufficient, adversely affecting the A/D conversion precision.

To satisfy the A/D conversion precision, a sufficient sampling time must be selected. The required sampling time (Tsamp) depends on the external driving impedance R_{ext} , the board capacitance of the A/D converter input pin C_{ext} and the AV_{CC} voltage level. The following replacement model can be used for the calculation:



Rext: External driving impedance

C_{ext}: Capacitance of PCB at A/D converter input

C_{VIN}: Analog input capacity (I/O, analog switch and ADC are contained)

R_{VIN}: Analog input impedance (I/O, analog switch and ADC are contained)

The following approximation formula for the replacement model above can be used: Tsamp = $7.62 \times (\text{Rext} \times \text{Cext} + (\text{Rext} + \text{R}_{\text{VIN}}) \times \text{C}_{\text{VIN}})$

- Do not select a sampling time below the absolute minimum permitted value. $(0.5\mu s \text{ for } 4.5V \le AV_{CC} \le 5.5V, 1.2\mu s \text{ for } 2.7V \le AV_{CC} \le 4.5V)$
- If the sampling time cannot be sufficient, connect a capacitor of about 0.1µF to the analog input pin.
- A big external driving impedance also adversely affects the A/D conversion precision due to the pin input leakage current IIL (static current before the sampling switch) or the analog input leakage current IAIN (total leakage current of pin input and comparator during sampling). The effect of the pin input leakage current IIL cannot be compensated by an external capacitor.
- The accuracy gets worse as |AVRH AVRL| becomes smaller.

(3) Definition of A/D Converter Terms

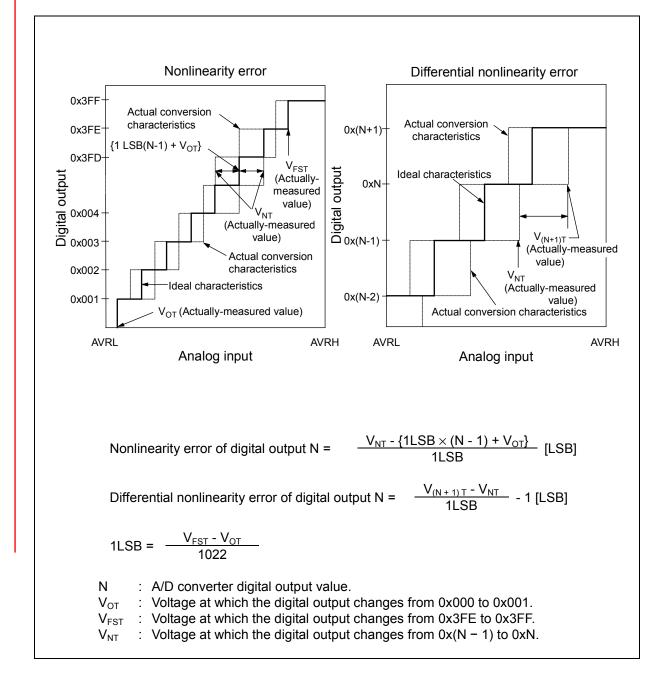
Resolution

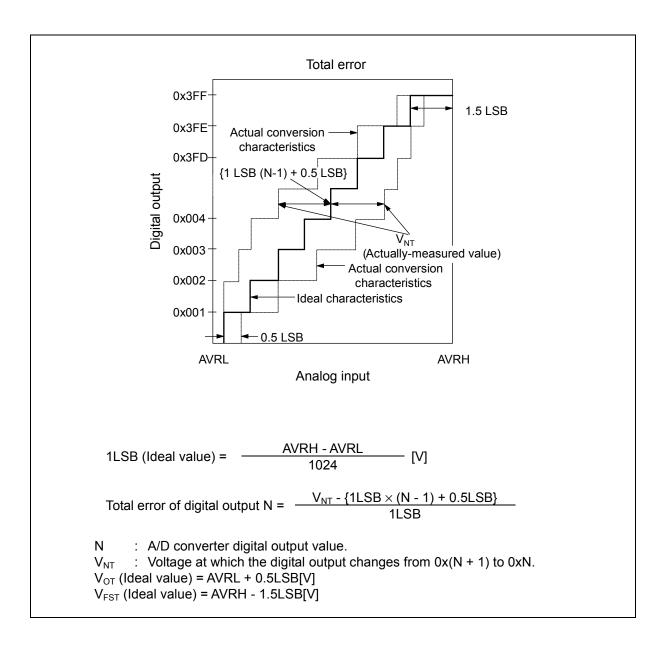
on : Analog variation that is recognized by an A/D converter.

• Nonlinearity error : Devi

: Deviation of the actual conversion characteristics from a straight line that connects

- the zero transition point (0b000000000 $\leftarrow \rightarrow$ 0b000000001) to the full-scale transition point (0b111111110 $\leftarrow \rightarrow$ 0b111111111).
- Differential nonlinearity error : Deviation from the ideal value of the input voltage that is required to change the output code by 1LSB.
- •Total error : Difference between the actual value and the theoretical value. The total error includes zero transition error, full-scale transition error and nonlinearity error.
- Zero transition voltage: Input voltage which results in the minimum conversion value.
- Full scale transition voltage: Input voltage which results in the maximum conversion value.

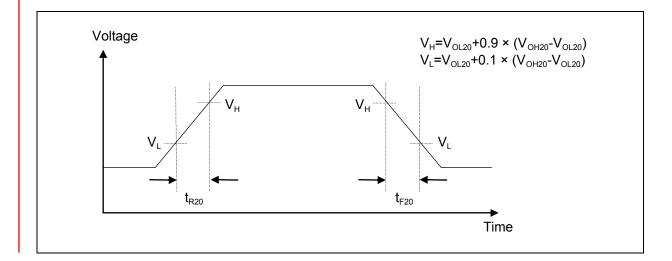




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6. High Current Output Slew Rate

			$(V_{CC} = AV_{CC} =$	2.7V to 5.	$5V, V_{SS} =$	$AV_{SS} = 0V$	$V, T_A =$	- 40°C to + 125°C)
Parameter	Symbol	Pin	Conditions		Value		Unit	Domorko
Falameter	Symbol	name	Conditions	Min	Тур	Max	Unit	Remarks
Output rise/fall time	t _{R20} , t _{F20}	P08_m, P09_m, P10_m	Outputs driving strength set to "20mA"	15	-	75	ns	C _L =85pF



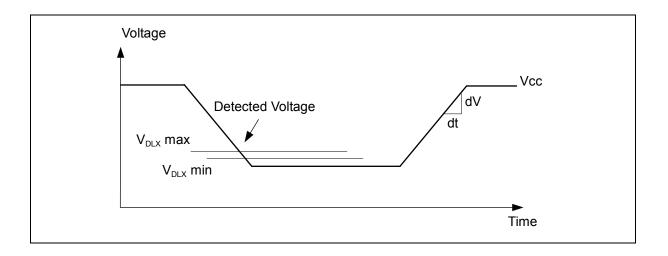
		$(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V)$	$V_{SS} = AV_{SS}$	$= 0V, T_{A} =$	= - 40°C to +	· 125°C)
Parameter	Symbol	Conditions		Unit		
Farameter	Symbol	Conditions	Min	Тур	Max	Onit
	V _{DL0}	$CILCR:LVL = 0000_B$	2.70	2.90	3.10	V
	V _{DL1}	$CILCR:LVL = 0001_B$	2.79	3.00	3.21	V
	V _{DL2}	$CILCR:LVL = 0010_B$	2.98	3.20	3.42	V
Detected voltage ^{*1}	V _{DL3}	$CILCR:LVL = 0011_B$	3.26	3.50	3.74	V
	V _{DL4}	$CILCR:LVL = 0100_B$	3.45	3.70	3.95	V
	V _{DL5}	$CILCR:LVL = 0111_B$	3.73	4.00	4.27	V
	V _{DL6}	$CILCR:LVL = 1001_B$	3.91	4.20	4.49	V
Power supply voltage change rate ^{*2}	dV/dt	-	- 0.004	-	+ 0.004	V/µs
II	N 7	CILCR:LVHYS=0	-	-	50	mV
Hysteresis width	$V_{\rm HYS}$	CILCR:LVHYS=1	80	100	120	mV
Stabilization time	T _{lvdstab}	-	_	-	75	μs
Detection delay time	t _d	-	-	-	30	μs

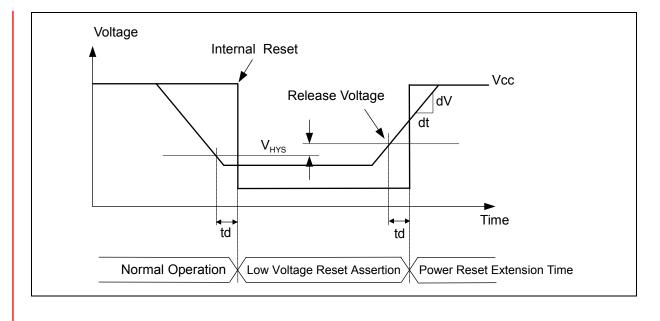
7. Low Voltage Detection Function Characteristics

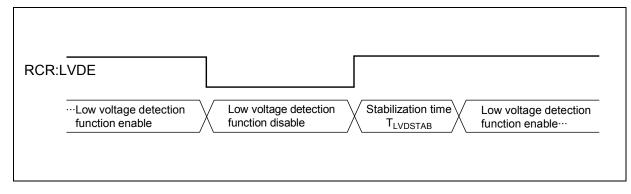
*1: If the power supply voltage fluctuates within the time less than the detection delay time (t_d), there is a possibility that the low voltage detection will occur or stop after the power supply voltage passes the detection range.

*2: In order to perform the low voltage detection at the detection voltage (V_{DLX}), be sure to suppress fluctuation of the power supply voltage within the limits of the change ration of power supply voltage.

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	$(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}C \text{ to } + 125^{\circ}C$						
Paran	neter	Conditions		Value	e	Unit	Remarks
Falai		Conditions	Min	Тур	Max	Unit	INCIDAINS
	Large Sector	$T_A\!\leq\!+105^\circ\!C$	-	1.6	7.5	s	
Sector erase time	Small Sector	-	-	0.4	2.1	s	Includes write time prior to internal erase.
	Security Sector	-	-	0.31	1.65	s	
Word (16-bit)	Large Sector	$T_A\!\leq\!+105^\circ\!C$	-	25	400	μs	Not including system-level overhead
write time	Small Sector	-	-	25	400	μs	time.
Chip erase time		$T_A \leq +105^{\circ}C$	-	8.31	40.05	S	Includes write time prior to internal erase.

8. Flash Memory Write/Erase Characteristics

Note: While the Flash memory is written or erased, shutdown of the external power (V_{CC}) is prohibited. In the application system where the external power (V_{CC}) might be shut down while writing or erasing, be sure to turn the power off by using a low voltage detection function.

To put it concrete, change the external power in the range of change ration of power supply voltage $(-0.004V/\mu s \text{ to } +0.004V/\mu s)$ after the external power falls below the detection voltage $(V_{DLX})^{*1}$.

Write/Erase cycles and data hold time

Write/Erase cycles	Data hold time
(cycle)	(year)
1,000	20 *2
10,000	10 *2
100,000	5 ^{*2}

*1: See "7. Low Voltage Detection Function Characteristics".

*2: This value comes from the technology qualification (using Arrhenius equation to translate high temperature measurements into normalized value at + 85°C).

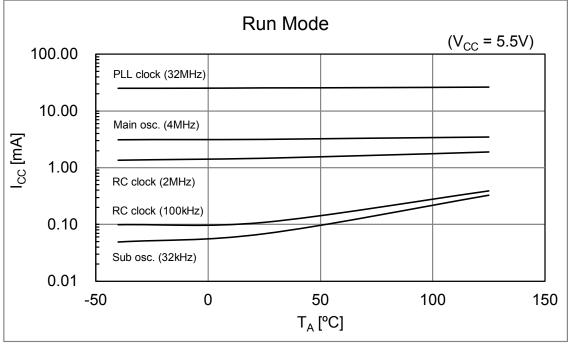
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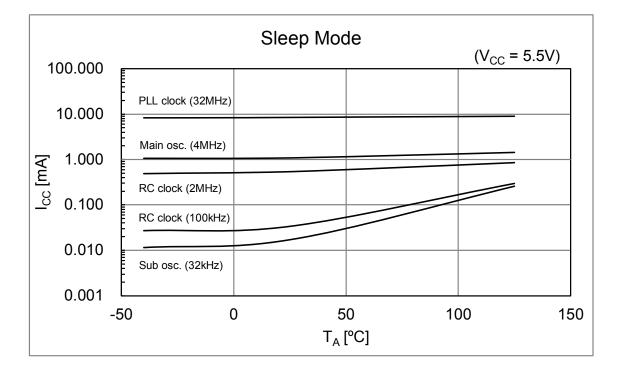
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EXAMPLE CHARACTERISTICS

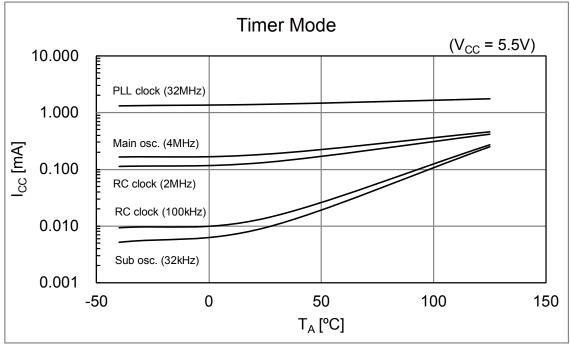
This characteristic is an actual value of the arbitrary sample. It is not the guaranteed value.

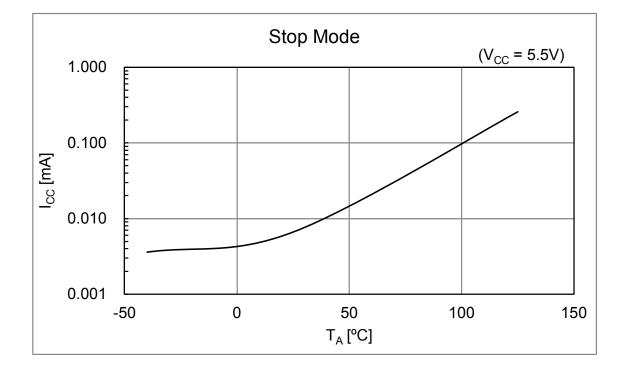
• MB96F6B6





• MB96F6B6





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• Used setting

Mode	Selected Source Clock	Clock/Regulator and FLASH Settings
Run mode	PLL	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 32MHz
	Main osc.	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 4MHz
	RC clock fast	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 2MHz
	RC clock slow	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 100kHz
	Sub osc.	CLKS1 = CLKS2 = CLKB = CLKP1 = CLKP2 = 32kHz
Sleep mode	PLL	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 32MHz
Sleep mode		Regulator in High Power Mode,
		(CLKB is stopped in this mode)
	Main osc.	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 4MHz
		Regulator in High Power Mode,
		(CLKB is stopped in this mode)
	RC clock fast	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 2MHz
		Regulator in High Power Mode,
		(CLKB is stopped in this mode)
	RC clock slow	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 100kHz
		Regulator in Low Power Mode,
		(CLKB is stopped in this mode)
	Sub osc.	CLKS1 = CLKS2 = CLKP1 = CLKP2 = 32kHz
		Regulator in Low Power Mode,
Timon mode	DLI	(CLKB is stopped in this mode) CLKMC = 4MHz, CLKPLL = 32MHz
Timer mode	PLL	(System clocks are stopped in this mode)
		Regulator in High Power Mode,
		FLASH in Power-down / reset mode
	Main osc.	CLKMC = 4MHz
	Wall ose.	(System clocks are stopped in this mode)
		Regulator in High Power Mode,
		FLASH in Power-down / reset mode
	RC clock fast	CLKMC = 2MHz
		(System clocks are stopped in this mode)
		Regulator in High Power Mode,
		FLASH in Power-down / reset mode
	RC clock slow	CLKMC = 100kHz
		(System clocks are stopped in this mode)
		Regulator in Low Power Mode,
		FLASH in Power-down / reset mode
	Sub osc.	CLKMC = 32 kHz
		(System clocks are stopped in this mode)
		Regulator in Low Power Mode,
<u>a.</u>		FLASH in Power-down / reset mode
Stop mode	stopped	(All clocks are stopped in this mode)
		Regulator in Low Power Mode,
		FLASH in Power-down / reset mode

ORDERING INFORMATION

MCU with CAN controller

Part number	Flash memory	Package*
MB96F6B5RBPMC-GSE1	Flash A	100-pin plastic LQFP
MB96F6B5RBPMC-GSE2	(160.5KB)	(FPT-100P-M20)
MB96F6B6RBPMC-GSE1	Flash A	100-pin plastic LQFP
MB96F6B6RBPMC-GSE2	(288.5KB)	(FPT-100P-M20)

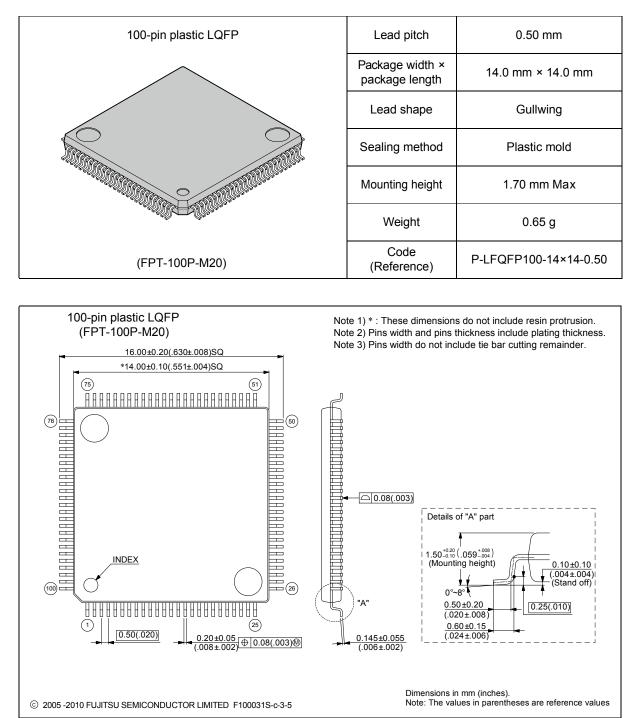
*: For details about package, see "■PACKAGE DIMENSION".

MCU without CAN controller

Part number	Flash memory	Package*
MB96F6B5ABPMC-GSE1	Flash A	100-pin plastic LQFP
MB96F6B5ABPMC-GSE2	(160.5KB)	(FPT-100P-M20)

*: For details about package, see "
PACKAGE DIMENSION".

PACKAGE DIMENSION



Please check the latest package dimension at the following URL. http://edevice.fujitsu.com/package/en-search/

■ MAJOR CHANGES IN THIS EDITION

Page	Section	Change Results
-	-	$PRELIMINARY \rightarrow Data sheet$
2	■FEATURES	Changed the description of "System clock" Up to 16 MHz external clock for devices with fast clock input feature
2		\rightarrow Up to 8 MHz external clock for devices with fast clock input feature
		Changed the description of "LCD Controller" On-chip drivers for internal divider resistors or external divider resistors →
		Internal divider resistors or external divider resistors Added "Sound Generator"
4		Changed the description of "External Interrupts"
		Interrupt mask and pending bit per channel \rightarrow
		Interrupt mask bit per channel
		Added the description of "I/O Ports"
		"Some pins offer high current output capability for LED
		driving."
		Changed the description of "Built-in On Chip Debugger"
-		- Event sequencer: 2 levels
5		\rightarrow
		- Event sequencer: 2 levels + reset
	■PRODUCT LINEUP	Added the Product
		Changed the Remark of RLT
(RLT 0/1/2/3/6 Only RLT6 can be used as PPG clock source
6		\rightarrow
		RLT 0 to 3/6
		Added the Feature of Sound Generator
	■BLOCK DIAGRAM	Added the block of Sound Generator
		Deleted the block of RLT6 from PPG block
8		Changed the RLT block
0		4ch
		\rightarrow
		0/1/2/3/6 5ch
	■PIN ASSIGNMENT	Added the Pin
		Pin no.23, SGO1
		Pin no.24, SGA1
9		Pin no.28, SGO1_R
		Pin no.29, SGA1_R
		Pin no.81, SGO0
		Pin no.82, SGA0
	■ PIN DESCRIPTION	Changed the Description of PPGn_B
		Programmable Pulse Generator n output (8bit)
		\rightarrow
		Programmable Pulse Generator n output (16bit/8bit)
10		Added the Pin
		SGAn
		SGAn_R
		SGOn
		SGOn_R

A change on a page is indicated by a vertical line drawn on the left side of that page.



Page	Section	Change Results
12	■PIN CIRCUIT TYPE	Added the Pin name Pin no.23, SGO1 Pin no.24, SGA1 Pin no.28, SGO1_R Pin no.29, SGA1_R
		Changed the I/O circuit type Pin no.30 to 34, 37 to 40 $K \rightarrow V$
13		Changed the I/O circuit type Pin no.41 to 43, 47, 49 $K \rightarrow V$ Pin no.46, 48 $I \rightarrow W$
14		Added the Pin name Pin no.81, SGO0 Pin no.82, SGA0
16	■I/O CIRCUIT TYPE	Changed the figure of type B Changed the Remarks of type B (CMOS hysteresis input with input shutdown function, $I_{OL} = 4mA$, $I_{OH} = -4mA$, Programmable pull-up resister) \rightarrow (CMOS level output ($I_{OL} = 4mA$, $I_{OH} = -4mA$), Automotive input with input shutdown function and programmable pull-up resistor)
17	-	Changed the figure of type G
20		Added the Type V
21		Added the Type W
22	■MEMORY MAP	Changed the START addresses of Boot-ROM $0F:E000_H$ \rightarrow $0F:C000_H$
24	■USER ROM MEMORY MAP FOR FLASH DEVICES	Changed the annotation Others (from DF:0200 _H to DF:1FFF _H) are all ROM Mirror area for SAS-512B. \rightarrow Others (from DF:0200 _H to DF:1FFF _H) is mirror area of SAS-512B.
26	■INTERRUPT VECTOR TABLE	Changed the Description of CALLV0 to CALLV7 Reserved → CALLV instruction Changed the Description of RESET Reserved → Reset vector Changed the Description of INT9 Reserved → INT9 instruction Changed the Description of EXCEPTION Reserved → Undefined instruction execution

Page	Section	Change Results
	■INTERRUPT VECTOR TABLE	Changed the Vector name of Vector number 64 PPGRLT \rightarrow
27		RLT6 Changed the Description of Vector number 64 Reload Timer 6 can be used as PPG clock source \rightarrow Reload Timer 6
28		Added Vector name to Vector number 95 SG0
29		Added Vector name to Vector number 121 SG1
30 to 33	■HANDLING PRECAUTIONS	Added a section
	■HANDLING DEVICES	Added the description to "3. External clock usage" (3) Opposite phase external clock
		Changed the description in "7. Turn on sequence of power supply to A/D converter and analog inputs"
35		In this case, the voltage must not exceed AVRH or AV_{CC} (turning the analog and digital power supplies simultaneously on or off is acceptable).
		In this case, AVRH must not exceed AV_{CC} . Input voltage for ports shared with analog input ports also must not exceed AV_{CC} (turning the analog and digital power supplies simultaneously on or off is acceptable).
36		Added the description "12. Mode Pin (MD)"
	■ELECTRICAL CHARACTERISTICS	Added Symbols of High current port
37	1. Absolute Maximum Ratings	Changed the annotation *3 Input/Output voltages of standard ports depend on V_{CC} .
		Input/Output voltages of general I/O ports depend on $V_{\text{CC}}.$
		Changed the annotation *4 Note that if the +B input is applied during power-on, the power supply is provided from the pins and the resulting supply voltage may not be sufficient to operate the Power reset (except devices with persistent low voltage reset in internal vector mode). \rightarrow
38		Note that if the +B input is applied during power-on, the power supply is provided from the pins and the resulting supply voltage may not be sufficient to operate the Power reset.
		Added the annotation *4 The DEBUG I/F pin has only a protective diode against V_{SS} . Hence it is only permitted to input a negative clamping current (4mA). For protection against positive input voltages, use an external clamping diode which limits the input voltage to maximum 6.0V.



Page	Section	Change Results
	2. Recommended Operating Conditions	Added the Value and Remarks to "Power supply voltage" Min: 2.0V Typ: -
		Max: 5.5V Remarks: Maintains RAM data in stop mode
39		Changed the Value of "Smoothing capacitor at C pin"
		Typ: $1.0\mu F \rightarrow 1.0\mu F$ to $3.9\mu F$
		Max: $1.5\mu F \rightarrow 4.7\mu F$
		Changed the Remarks of "Smoothing capacitor at C pin" Deleted "(Target value)"
		Added " 3.9μ F (Allowance within $\pm 20\%$)"
	3. DC Characteristics	Deleted "(Target value)" from Remarks
	(1) Current Rating	Added the Symbol to "Power supply current in Run modes"
		I _{CCRCH} , I _{CCRCL}
		Changed the Conditions of I _{CCPLL} , I _{CCMAIN} , I _{CCSUB} in "Power
		supply current in Run modes" "Flash 0 wait" is added
		Changed the Value of "Power supply current in Run modes"
40		I_{CCPLL} TYP:28.5mA \rightarrow 28mA (T _A = +25°C)
		I_{CCMAIN} TYP:5mA \rightarrow 3.5mA (T _A = +25°C)
		Max: $10\text{mA} \rightarrow 8\text{mA}$ (T _A = +105°C) Max: 11 5 m A $\rightarrow 0.5$ m A (T _A = +125°C)
		Max: 11.5mA \rightarrow 9.5mA (T _A = +125°C) I _{CCSUB}
		$TYP:0.5mA \rightarrow 0.1mA (T_A = +25^{\circ}C)$
		Max: $6mA \rightarrow 3.3mA$ ($T_A = +105^{\circ}C$)
	-	Max: 7.5mA \rightarrow 4.8mA (T _A = +125°C)
		Added the Symbol to "Power supply current in Sleep modes" I_{CCSRCH} , I_{CCSRCL}
		Changed the Conditions of I _{CCSMAIN} in "Power supply current in Sleep modes"
		"SMCR:LPMSS=0" is added
		Changed the Value of "Power supply current in Sleep modes"
41		I_{CCSPLL} Typ: 10mA \rightarrow 9.5mA (T _A = +25°C)
		I_{CCSMAIN}
		Typ: $3mA \rightarrow 1.1mA$ (T _A = +25°C) Max: $8mA \rightarrow 4.7mA$ (T _A = +105°C)
		Max: 9.5mA \rightarrow 6.2mA (T _A = +125°C)
		I _{CCSSUB}
		Typ: $0.3\text{mA} \rightarrow 0.04\text{mA}$ (T _A = +25°C) Married 5 mA $\rightarrow 2.7$ mA (T _A = +105°C)
		Max: $4.5\text{mA} \rightarrow 2.7\text{mA}$ (T _A = +105°C) Max: $6\text{mA} \rightarrow 4.2\text{mA}$ (T _A = +125°C)
42	4	Added the Symbol to "Power supply current in Timer modes"
		I _{CCTPLL}
		Changed the Conditions of I _{CCTMAIN} , I _{CCTRCH} in "Power supply
		current in Timer modes"
		"SMCR:LPMSS=0" is added

Page	Section	Change Results
-	3. DC Characteristics (1) Current Rating	Changed the Value of "Power supply current in Timer modes" $I_{CCTMAIN}$ Man 2250 A (T = 125°C)
42		$\begin{array}{ll} Max: 335\mu A \to 330\mu A & (T_A = +25^{\circ} C) \\ Max: 1320\mu A \to 1200\mu A & (T_A = +105^{\circ} C) \\ Max: 2300\mu A \to 2155\mu A & (T_A = +125^{\circ} C) \end{array}$
		I_{CCTRCH} Max: 245µA \rightarrow 215µA (T _A = +25°C) Max: 1230µA \rightarrow 1110µA (T _A = +105°C) Max: 2205µA \rightarrow 2065µA (T _A = +125°C)
		I_{CCTRCL} Max: 105µA \rightarrow 75µA (T _A = +25°C) Max: 1030µA \rightarrow 910µA (T _A = +105°C) Max: 2005µA \rightarrow 1870µA (T _A = +125°C)
		I_{CCTSUB} Max: 90µA \rightarrow 65µA (T _A = +25°C) Max: 1000µA \rightarrow 885µA (T _A = +105°C) Max: 1980µA \rightarrow 1845µA (T _A = +125°C)
		Changed the Value of "Power supply current in Stop mode" I_{CCH} Max: 90 μ A \rightarrow 60 μ A (T _A = +25°C)
		Max: $1000\mu A \rightarrow 880\mu A$ (T _A = +105°C) Max: $1980\mu A \rightarrow 1840\mu A$ (T _A = +125°C)
		Added the Symbol I _{CCFLASHPD}
		Changed the Value and condition of "Power supply current for active Low Voltage detector"
		I_{CCLVD} Typ: 5µA, Max: 15µA, Remarks: nothing \rightarrow
		Typ: 5µA, Max: -, Remarks: $T_A = +25^{\circ}C$ Typ: -, Max: 12.5µA, Remarks: $T_A = +125^{\circ}C$
43		Changed the condition of "Flash Write/Erase current" I _{CCFLASH} Typ: 12.5mA, Max: 20mA, Remarks: nothing
		\rightarrow Typ: 12.5mA, Max: -, Remarks: T _A = +25°C Typ: -, Max: 20mA, Remarks: T _A = +125°C
		Changed the annotation *2 The power supply current is measured with a 4MHz external clock connected to the Main oscillator and a 32kHz external clock connected to the Sub oscillator.
		\rightarrow When Flash is not in Power-down / reset mode, I _{CCFLASHPD} must be added to the Power supply current. The power supply current is measured with a 4MHz external clock connected to the Main oscillator and a 32kHz external clock connected to the Sub oscillator. The current for "On Chip
		Debugger" part is not included.
4.4	3. DC Characteristics(2) Pin Characteristics	Added the Symbol for High Drive type V_{OH20} , V_{OL20}
44		Added the Symbol for DEBUG I/F pin V_{OLD}

Page	Section	Change Results
Page 45	Section 3. DC Characteristics (2) Pin Characteristics	Changed the Pin name of "Input capacitance" Other than Vcc, Vss, AVcc, AVss, AVRH, AVRL, P08_m, P09_m, P10_m \rightarrow Other than C, Vcc, Vss, AVcc, AVss, AVcc, AVss, AVcc, Varther than C, Vcc, Vss, AVcc, AVss, AVRH, P08_m, P09_m, P10_m \rightarrow Other than C, Vcc, Vss, AVRL, P08_m, P09_m, P10_m \rightarrow Other than C, Vcc, Vss, AVRL, P08_m, P09_m, P10_m \rightarrow Other than C, Vcc, Vss, AVRL, P08_m, P09_m, P10_m \rightarrow Other than C, Vcc, Vss, AVRL, P08_m, P09_m, P10_m \rightarrow Other than C, Vcc, Vss, AVRL, P08_m, P09_m, P10_m \rightarrow Other than C, Vcc, Vss, AVRL, P08_m, P09_m, P10_m \rightarrow Other than C, Vcc, Vss, AVRL, P08_m, P09_m, P10_m \rightarrow Deleted the annotation
46	4. AC Characteristics (1) Main Clock Input Characteristics	"IOH and IOL are target value."Added the annotation"In the case of high current outputs, set "1" to the bit in the Port High Drive Register."Changed MAX frequency for f_{FCI} in all conditions $16 \rightarrow 8$ Changed MIN frequency for t_{CYLH} 62.5 \rightarrow 125Changed MIN, MAX and Unit for P_{WH} , P_{WL} MIN: 30 \rightarrow 55MAX: 70 \rightarrow - Unit: % \rightarrow ns
47	4. AC Characteristics(2) Sub Clock Input Characteristics	Added the figure (t _{CYLH}) when using the external clock Added the figure (t _{CYLL}) when using the crystal oscillator clock
48	4. AC Characteristics (3) Built-in RC Oscillation Characteristics	Added "RC clock stabilization time"
49	4. AC Characteristics(5) Operating Conditions of PLL	Changed the Value of "PLL input clock frequency"Max: 16MHz \rightarrow 8MHzChanged the Symbol of "PLL oscillation clock frequency" $f_{PLLO} \rightarrow f_{CLKVCO}$ Added Remarks to "PLL oscillation clock frequency"Added " PLL phase jitter" and the figure
	4. AC Characteristics(6) Reset Input	Added the figure for reset input time (t_{RSTL})

Page	Section	Change Results
	4. AC Characteristics(8) USART Timing	Changed the condition $(V_{CC} = AV_{CC} = 2.7V \text{ to } 5.5V, V_{SS} = AV_{SS} = 0V, T_A = -40^{\circ}C \text{ to}$ $+ 125^{\circ}C)$
51		\rightarrow (V _{CC} = AV _{CC} = 2.7V to 5.5V, V _{SS} = AV _{SS} = 0V, T _A = -40°C to + 125°C, C _L =50pF)
		Changed the HARDWARE MANUAL "MB966B0 series HARDWARE MANUAL" →
52	-	"MB96600 series HARDWARE MANUAL" Changed the figure for "Internal shift clock mode"
52	4. AC Characteristics	Added parameter, "Noise filter" and an annotation *5 for it
54	(10) I ² C timing	Added t_{SP} to the figure
	5. A/D Converter	
55	(1) Electrical Characteristics for	Added "Analog impedance" Added "Variation between channels"
55	the A/D Converter	
	5 A/D Consumption	Added the annotation
56	5. A/D Converter(2) Accuracy and Setting of the	Deleted the unit "[Min]" from approximation formula of Sampling time
50	A/D Converter Sampling Time	Sampling time
	5. A/D Converter	Changed the Description and the figure
	(3) Definition of A/D Converter	"Linearity" \rightarrow "Nonlinearity"
	Terms	"Differential linearity error"
		→ "Differential nonlinearity error"
		Changed the Description
		Linearity error:
		Deviation of the line between the zero-transition point
		$(0b000000000 \leftrightarrow \rightarrow 0b000000001)$ and the full-scale
57		transition point (0b111111110 \leftrightarrow -)0b111111111) from the
		actual conversion characteristics.
		→ Nonlinearity error:
		Deviation of the actual conversion characteristics from a
		straight line that connects the zero transition point
		$(0b000000000 \leftrightarrow \rightarrow 0b000000001)$ to the full-scale
		transition point (0b111111110 $\leftarrow \rightarrow$ 0b111111111).
		Added the Description
		"Zero transition voltage" "Full scale transition voltage"
	6. High Current Output Slew	
59	Rate	Added the item of "6. High Current Output Slew Rate"
	7. Low Voltage Detection	Added the Value of "Power supply voltage change rate"
	Function Characteristics	$Max: +0.004 V/\mu s$
60		Added "Hysteresis width" (V _{HYS}) Added "Stabilization time" (T _{LVDSTAB})
		Added "Detection delay time" $(t_{LVDSTAB})$
		Deleted the Remarks
		Added the annotation *1, *2
61		Added the figure for "Hysteresis width"
01		Added the figure for "Stabilization time"

Page	Section	Change Results
	8. Flash Memory Write/Erase Characteristics	Changed the Value of "Sector erase time"
		Added "Security Sector" to "Sector erase time"
		Changed the Parameter "Half word (16 bit) write time" → "Word (16-bit) write time"
62		Changed the Value of "Chip erase time"
	02	Changed the Remarks of "Sector erase time" Excludes write time prior to internal erase → Includes write time prior to internal erase
		Added the Note and annotation *1
		Deleted "(targeted value)" from title "Write/Erase cycles and data hold time"
63 to 65	■EXAMPLE CHARACTERISTICS	Added a section
	■ORDERING INFORMATION	Changed part number • MCU with CAN controller MB96F6B6RAPMC-GSE1* → MB96F6B6RBPMC-GSE1 MB96F6B6RAPMC-GSE2* → MB96F6B6RBPMC-GSE2
66		Added part number • MCU with CAN controller MB96F6B5RBPMC-GSE1 MB96F6B5RBPMC-GSE2 • MCU without CAN controller MB96F6B5ABPMC-GSE1 MB96F6B5ABPMC-GSE2

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